

LPC546xx

32-bit ARM Cortex-M4 microcontroller; up to 512 KB flash and 200 kB SRAM; High-speed USB device/host + PHY; Full-speed USB device/host; Ethernet AVB; LCD; EMC; SPIFI; CAN FD, SDIO; SHA; 12-bit 5 Msamples/s ADC; DMIC subsystem

Rev. 2.6 — 23 October 2018 Product data sheet

1. General description

The LPC546xx is a family of ARM Cortex-M4 based microcontrollers for embedded applications featuring a rich peripheral set with very low power consumption and enhanced debug features.

The ARM Cortex-M4 is a 32-bit core that offers system enhancements such as low power consumption, enhanced debug features, and a high level of support block integration. The ARM Cortex-M4 CPU incorporates a 3-stage pipeline, uses a Harvard architecture with separate local instruction and data buses as well as a third bus for peripherals, and includes an internal prefetch unit that supports speculative branching. The ARM Cortex-M4 supports single-cycle digital signal processing and SIMD instructions. A hardware floating-point processor is integrated into the core.

The LPC546xx family includes up to 512 KB of flash, 200 KB of on-chip SRAM, up to 16 kB of EEPROM memory, a quad SPI Flash Interface (SPIFI) for expanding program memory, one high-speed and one full-speed USB host and device controller, Ethernet AVB, LCD controller, Smart Card Interfaces, SD/MMC, CAN FD, an External Memory Controller (EMC), a DMIC subsystem with PDM microphone interface and I2S, five general-purpose timers, SCTimer/PWM, RTC/alarm timer, Multi-Rate Timer (MRT), a Windowed Watchdog Timer (WWDT), ten flexible serial communication peripherals (USART, SPI, I2S, I2C interface), Secure Hash Algorithm (SHA), 12-bit 5.0 Msamples/sec ADC, and a temperature sensor.

2. Features and benefits

- ARM Cortex-M4 core (version r0p1):
	- ◆ ARM Cortex-M4 processor, running at a frequency of up to 220 MHz.
	- ◆ The LPC5460x/61x devices operate at CPU frequencies of up to 180 MHz. The LPC54628 device operates at CPU frequencies of up to 220 MHz.
	- ◆ Floating Point Unit (FPU) and Memory Protection Unit (MPU).
	- ARM Cortex-M4 built-in Nested Vectored Interrupt Controller (NVIC).
	- Non-maskable Interrupt (NMI) input with a selection of sources.
	- \blacklozenge Serial Wire Debug (SWD) with six instruction breakpoints, two literal comparators, and four watch points. Includes Serial Wire Output and ETM Trace for enhanced debug capabilities, and a debug timestamp counter.
	- ◆ System tick timer.

- On-chip memory:
	- Up to 512 KB on-chip flash program memory with flash accelerator and 256 byte page erase and write.
	- ◆ Up to 200 KB total SRAM consisting of 160 KB contiguous main SRAM and an additional 32 KB SRAM on the I&D buses. 8 KB of SRAM bank intended for USB traffic.
	- ◆ 16 KB of EEPROM.
- ROM API support:
	- ◆ Flash In-Application Programming (IAP) and In-System Programming (ISP).
	- ◆ ROM-based USB drivers (HID, CDC, MSC, and DFU). Flash updates via USB.
	- ◆ Booting from valid user code in flash, USART, SPI, and I²C.
	- ◆ Legacy, Single, and Dual image boot.
	- ◆ OTP API for programming OTP memory.
	- ◆ Random Number Generator (RNG) API.
- Serial interfaces:
	- Flexcomm Interface contains up to ten serial peripherals. Each Flexcomm Interface can be selected by software to be a USART, SPI, or I ²C interface. Two Flexcomm Interfaces also include an I2S interface. Each Flexcomm Interface includes a FIFO that supports USART, SPI, and I²S if supported by that Flexcomm Interface. A variety of clocking options are available to each Flexcomm Interface and include a shared fractional baud-rate generator.
	- ◆ I²C-bus interfaces support Fast-mode and Fast-mode Plus with data rates of up to 1Mbit/s and with multiple address recognition and monitor mode. Two sets of true I ²C pads also support High Speed Mode (3.4 Mbit/s) as a slave.
	- ◆ Two ISO 7816 Smart Card Interfaces with DMA support.
	- USB 2.0 high-speed host/device controller with on-chip high-speed PHY.
	- USB 2.0 full-speed host/device controller with on-chip PHY and dedicated DMA controller supporting crystal-less operation in device mode using software library. See Technical note TN00032 for more details.
	- ◆ SPIFI with XIP feature uses up to four data lines to access off-chip SPI/DSPI/QSPI flash memory at a much higher rate than standard SPI or SSP interfaces.
	- Ethernet MAC with MII/RMII interface with Audio Video Bridging (AVB) support and dedicated DMA controller.
	- ◆ Two CAN FD modules with dedicated DMA controller.
- Digital peripherals:
	- ◆ DMA controller with 30 channels and up to 24 programmable triggers, able to access all memories and DMA-capable peripherals.
	- ◆ LCD Controller supporting both Super-Twisted Nematic (STN) and Thin-Film Transistor (TFT) displays. It has a dedicated DMA controller, selectable display resolution (up to 1024 x 768 pixels), and supports up to 24-bit true-color mode.
	- ◆ External Memory Controller (EMC) provides support for asynchronous static memory devices such as RAM, ROM and flash, in addition to dynamic memories such as single data rate SDRAM with an SDRAM clock of up to 100 MHz. EMC bus width (bit) on TFBGA180, TFBGA100, and LQFP100 and packages supports up to 8/16 data line wide static memory, in addition to dynamic memories, such as, SDRAM (2 banks only) with an SDRAM clock of up to 100 MHz.
	- ◆ Secured digital input/output (SD/MMC and SDIO) card interface with DMA support.
- ◆ CRC engine block can calculate a CRC on supplied data using one of three standard polynomials with DMA support.
- ◆ Up to 171 General-Purpose Input/Output (GPIO) pins.
- GPIO registers are located on the AHB for fast access. The DMA supports GPIO ports.
- \blacklozenge Up to eight GPIOs can be selected as Pin Interrupts (PINT), triggered by rising, falling or both input edges.
- ◆ Two GPIO Grouped Interrupts (GINT) enable an interrupt based on a logical (AND/OR) combination of input states.
- ◆ CRC engine.
- Analog peripherals:
	- \triangle 12-bit ADC with 12 input channels and with multiple internal and external trigger inputs and sample rates of up to 5.0 MSamples/sec. The ADC supports two independent conversion sequences.
	- \blacklozenge Integrated temperature sensor connected to the ADC.
- DMIC subsystem including a dual-channel PDM microphone interface, flexible decimators, 16 entry FIFOs, optional DC locking, hardware voice activity detection, and the option to stream the processed output data to 12 S.
- **Timers:**
	- ◆ Five 32-bit general purpose timers/counters, four of which support up to four capture inputs and four compare outputs, PWM mode, and external count input. Specific timer events can be selected to generate DMA requests. The fifth timer does not have external pin connections and may be used for internal timing operations.
	- ◆ SCTimer/PWM with 8 input and 10 output functions (including capture and match). Inputs and outputs can be routed to/from external pins and internally to or from selected peripherals. Internally, the SCTimer/PWM supports 10 match/captures, 10 events, and 10 states.
	- ◆ 32-bit Real-time clock (RTC) with 1 s resolution running in the always-on power domain. A timer in the RTC can be used for wake-up from all low power modes including deep power-down, with 1 ms resolution.
	- \blacklozenge Multiple-channel multi-rate 24-bit timer (MRT) for repetitive interrupt generation at up to four programmable, fixed rates.
	- Windowed Watchdog Timer (WWDT).
	- ◆ Repetitive Interrupt Timer (RIT) for debug time stamping and for general purpose use.
- Security features:
	- ◆ enhanced Code Read Protection (eCRP) to protect user code.
	- ◆ OTP memory for ECRP settings, and user application specific data.
	- ◆ Secure Hash Algorithm (SHA1/SHA2) module with dedicated DMA controller.
- Clock generation:
	- ◆ 12 MHz internal Free Running Oscillator (FRO). This oscillator provides a selectable 48 MHz or 96 MHz output, and a 12 MHz output (divided down from the selected higher frequency) that can be used as a system clock. The FRO is trimmed to ± 1 % accuracy over the entire voltage and temperature range.
	- ◆ External clock input for clock frequencies of up to 25 MHz.
	- Crystal oscillator with an operating range of 1 MHz to 25 MHz.
- ◆ Watchdog Oscillator (WDTOSC) with a frequency range of 6 kHz to 1.5 MHz.
- ◆ 32.768 kHz low-power RTC oscillator.
- ◆ System PLL allows CPU operation up to the maximum CPU rate and can run from the main oscillator, the internal FRO, the watchdog oscillator or the 32.768 KHz RTC oscillator.
- Two additional PLLs for USB clock and audio subsystem.
- Independent clocks for the SPIFI interface, ADC, USBs, and the audio subsystem.
- ◆ Clock output function with divider.
- ◆ Frequency measurement unit for measuring the frequency of any on-chip or off-chip clock signal.
- **Power control:**
	- ◆ Programmable PMU (Power Management Unit) to minimize power consumption and to match requirements at different performance levels.
	- Reduced power modes: sleep, deep-sleep, and deep power-down.
	- Wake-up from deep-sleep modes due to activity on the USART, SPI, and I2C peripherals when operating as slaves.
	- Ultra-low power Micro-tick Timer, running from the Watchdog oscillator that can be used to wake up the device from low power modes.
	- ◆ Power-On Reset (POR).
	- ◆ Brown-Out Detect (BOD) with separate thresholds for interrupt and forced reset.
- Single power supply 1.71 V to 3.6 V.
- Power-On Reset (POR).
- Brown-Out Detect (BOD) with separate thresholds for interrupt and forced reset.
- **JTAG boundary scan supported.**
- 128 bit unique device serial number for identification.
- Operating temperature range -40 °C to $+105$ °C.
- Available in TFBGA180, TFBGA100, LQFP208, and LQFP100 packages.

3. Ordering information

Table 1. Ordering information

3.1 Ordering options

4. Marking

The LPC546xx TFBGA180 and TFBGA100 packages have the following top-side marking:

- **•** First line: LPC546xxJyyy
	- **–** yyy: flash size
- **•** Second line: ET180 or ET100
- **•** Third line: xxxxxxxxxxxx
- **•** Fourth line: xxxyywwx[R]x
	- **–** yyww: Date code with yy = year and ww = week.
	- **–** xR = boot code version and device revision.

The LPC546xx LQFP208 and LQFP100 packages have the following top-side marking:

- **•** First line: LPC546xxJyyy
	- **–** yyy: flash size
- **•** Second line: BD208 or BD100
- **•** Third line: xxxxxxxxxxxx
- **•** Fourth line: xxxyywwx[R]x

- **–** yyww: Date code with yy = year and ww = week.
- **–** xR = Boot code version and device revision.

Table 3. Device revision table

5. Block diagram

[Figure 4](#page-9-0) shows the LPC546xx block diagram. In this figure, orange shaded blocks support general purpose DMA and yellow shaded blocks include dedicated DMA control.

6. Pinning information

6.1 Pinning

6.2 Pin description

On the LPC546xx, digital pins are grouped into several ports. Each digital pin can support several different digital functions (including General Purpose I/O (GPIO)) and an additional analog function.

Symbol Description100-pin, TFBGA **100-pin, TFBGA** 80-pin, TFBGA **180-pin, TFBGA 100-pin, LQFP 208-pin, LQFP** Ξ **Reset state [1]** Reset state **Type** PIO1 10 H6 N9 84 41 2 PU I/O **PIO1 10** — General-purpose digital input/output pin. O **ENET_TXD1 —** Ethernet transmit data 1. I/O **FC1_RXD_SDA_MOSI —** Flexcomm 1: USART receiver, I2C data I/O, SPI master-out/slave-in data. O **CT1_MAT0 —** Match output 0 from Timer 1. O **SCT0_OUT3 —** SCTimer/PWM output 3. **R —** Reserved. O **EMC_RASN —** External memory interface row address strobe (active low). PIO1 11 B4 B4 198 94 **[\[2\]](#page-52-1)[\[8\]](#page-52-4) PU I/O PIO1 11** — General-purpose digital input/output pin. O **ENET_TX_EN —** Ethernet transmit enable (RMII/MII interface). I/O **FC1_TXD_SCL_MISO —** Flexcomm 1: USART transmitter, I2C clock, SPI master-in/slave-out data. **CT1_CAP1 — Capture 1 input to Timer 1. USB0 VBUS — Monitors the presence of USB0 bus power. R —** Reserved. O **EMC_CLK[0] —** External memory interface clock 0. PIO1 12 F8 K9 128 62 ² PU I/O **PIO1_12 —** General-purpose digital input/output pin. **ENET_RXD0 — Ethernet receive data 0.** I/O **FC6_SCK —** Flexcomm 6: USART, SPI, or I2S clock. O **CT1_MAT1 —** Match output 1 from Timer 1. O **USB0_PORTPWRN —** USB0 VBUS drive indicator (Indicates VBUS must be driven). O **EMC_DYCSN[0] —** External Memory interface SDRAM chip select 0 (active low). PIO1 13 **D10 G10 139 66 2** PU I/O **PIO1 13 —** General-purpose digital input/output pin. **ENET_RXD1 — Ethernet receive data 1.** I/O **FC6_RXD_SDA_MOSI_DATA —** Flexcomm 6: USART receiver, I2C data I/O, SPI master-out/slave-in data, I2S data I/O. I **CT1_CAP2 —** Capture 2 input to Timer 1. **I** USB0 OVERCURRENTN — USB0 bus overcurrent indicator (active low). O **USB0_FRAME —** USB0 frame toggle signal. O **EMC_DQM[0] —** External memory interface data mask 0.

Symbol Description00-pin, TFBGA **100-pin, TFBGA** 80-pin, TFBGA **180-pin, TFBGA 100-pin, LQFP 208-pin, LQFP** Ξ **Reset state [1]** Reset state **Type** PIO3_1 - D11 159 - **2** PU I/O **PIO3_1** — General-purpose digital input/output pin. O **LCD_VD[15] —** LCD Data [15]. I **PDM0_DATA —** Data for PDM interface 0 (digital microphone). **R —** Reserved. O **CT1_MAT1 —** Match output 1 from Timer 1. PIO3_2 - C10 164 - [\[2\]](#page-52-1) PU I/O **PIO3_2 —** General-purpose digital input/output pin. O **LCD_VD[16] —** LCD Data [16]. I/O **FC9_RXD_SDA_MOSI —** Flexcomm 9: USART receiver, I2C data I/O, SPI master-out/slave-in data. **R —** Reserved. O **CT1_MAT2 —** Match output 2 from Timer 1. PIO3 3 \vert - A13 169 - \vert 2 PU I/O **PIO3 3** — General-purpose digital input/output pin. O **LCD_VD[17] —** LCD Data [17]. I/O **FC9_TXD_SCL_MISO —** Flexcomm 9: USART transmitter, I2C clock, SPI master-in/slave-out data. PIO3 4 \vert - B11 172 - \vert PU I/O **PIO3 4** — General-purpose digital input/output pin. O **LCD_VD[18] —** LCD Data [18]. **R —** Reserved. I/O **FC8_CTS_SDA_SSEL0 —** Flexcomm 8: USART clear-to-send, I2C data I/O, SPI Slave Select 0. **CT4 CAP1 — Capture input 4 to Timer 1.** PIO3 5 - B10 177 - **2** PU I/O **PIO3 5** — General-purpose digital input/output pin. O **LCD_VD[19] —** LCD Data [19]. **R —** Reserved. I/O **FC8_RTS_SCL_SSEL1 —** Flexcomm 8: USART request-to-send, I2C clock, SPI slave select 1. O **CT4_MAT1 —** Match output 1 from Timer 4. PIO3_6 - C9 180 - ^{[\[2\]](#page-52-1)} PU I/O **PIO3_6** — General-purpose digital input/output pin. O **LCD_VD[20] —** LCD Data [20]. O **LCD_VD[0] —** LCD Data [0]. **R —** Reserved. O **CT4_MAT2 —** Match output 2 from Timer 4. PIO3 7 \vert - B8 184 - \vert 2 PU I/O **PIO3_7** — General-purpose digital input/output pin. O **LCD_VD[21] —** LCD Data [21]. O **LCD_VD[1] —** LCD Data [1]. **R —** Reserved. I **CT4_CAP2 —** Capture input 2 to Timer 4.

Symbol	100-pin, TFBGA	180-pin, TFBGA	208-pin, LQFP	100-pin, LQFP		state ^[1] Reset	Type	Description
PIO3_29		L13	112		$[2]$	PU	I/O	PIO3_29 - General-purpose digital input/output pin.
								R – Reserved.
							O	SCT0 OUT3 - SCTimer/PWM output 3.
							I/O	FC4 RTS SCL SSEL1 - Flexcomm 4: USART request-to-send, I2C clock, SPI slave select 1.
								R - Reserved.
								R – Reserved.
							O	EMC A[18] — External memory interface address 18.
PIO3 30		K ₁₃	116			PU	$ $ I/O	PIO3 30 - General-purpose digital input/output pin.
							I/O	FC9 CTS SDA SSEL0 - Flexcomm 9: USART clear-to-send, I2C data I/O, SPI Slave Select 0.
							O	SCT0_OUT4 - SCTimer/PWM output 4.
							I/O	FC4 SSEL2 - Flexcomm 4: SPI slave select 2.
								R – Reserved.
								R – Reserved.
							O	EMC A[19] — External memory interface address 19.
PIO3_31		J14	123		$[2]$	PU	I/O	PIO3_31 - General-purpose digital input/output pin.
							I/O	FC9 RTS SCL SSEL1 - Flexcomm 9: USART request-to-send, I2C clock, SPI slave select 1.
							O	SCT0 OUT5 - SCTimer/PWM output 5.
							O	CT4 MAT2 - Match output 2 from Timer 4.
								R – Reserved.
							L	SCT0_GPI0 - Pin input 0 to SCTimer/PWM.
							O	EMC_A[20] - External memory interface address 20.
PIO4 0		H ₁₃	127		$[2]$	PU I/O	PIO4 0 - General-purpose digital input/output pin.	
								R - Reserved.
							I/O	FC6 CTS SDA SSEL0 - Flexcomm 6: USART clear-to-send, I2C data I/O, SPI Slave Select 0.
							L	CT4 CAP1 - Capture input 4 to Timer 1.
								R – Reserved.
							L	SCT0_GPI1 - Pin input 1 to SCTimer/PWM.
							O	EMC_CSN[1] — External memory interface static chip select 1(active low).

Table 4. Pin description *…continued*

Table 4. Pin description *…continued*

32-bit ARM Cortex-M4 microcontroller

- [1] PU = input mode, pull-up enabled (pull-up resistor pulls up pin to V_{DD}). Z = high impedance; pull-up or pull-down disabled, AI = analog input, I = input, O = output, F = floating. Reset state reflects the pin state at reset without boot code operation. For pin states in the different power modes, see Section 6.2.2 "Pin states in different power modes". For termination on unused pins, see Section 6.2.1 "Termination of unused pins".
- [2] 5 V tolerant pad with programmable glitch filter (5 V tolerant if V_{DD} present; if V_{DD} not present, do not exceed 3.6 V); provides digital I/O functions with TTL levels and hysteresis; normal drive strength. See [Figure 44](#page-143-0). Pulse width of spikes or glitches suppressed by input filter is from 3 ns to 16 ns (simulated value).
- [3] True open-drain pin. I2C-bus pins compliant with the I2C-bus specification for I2C standard mode, I2C Fast-mode, and I2C Fast-mode Plus. The pin requires an external pull-up to provide output functionality. When power is switched off, this pin is floating and does not disturb the I2C lines. Open-drain configuration applies to all functions on this pin.
- [4] 5 V tolerant pin providing standard digital I/O functions with configurable modes, configurable hysteresis, and analog input. When configured as an analog input, the digital section of the pin is disabled, and the pin is not 5 V tolerant.
- [5] Reset pad.5 V tolerant pad with glitch filter with hysteresis. Pulse width of spikes or glitches suppressed by input filter is from 3 ns to 20 ns (simulated value)
- [6] 5 V tolerant transparent analog pad.
- [7] The oscillator input pin (XTALIN) cannot be driven by an external clock. Must connect a crystal between XTALIN and XTALOUT.
- [8] VBUS must be connected to supply voltage when using the USB peripheral.

6.2.1 Termination of unused pins

[Table 5](#page-52-8) shows how to terminate pins that are **not** used in the application. In many cases, unused pins should be connected externally or configured correctly by software to minimize the overall power consumption of the part.

Unused pins with GPIO function should be configured as outputs set to LOW with their internal pull-up disabled. To configure a GPIO pin as output and drive it LOW, select the GPIO function in the IOCON register, select output in the GPIO DIR register, and write a 0 to the GPIO PORT register for that pin. Disable the pull-up in the pinís IOCON register.

In addition, it is recommended to configure all GPIO pins that are not bonded out on smaller packages as outputs driven LOW with their internal pull-up disabled.

Table 5. Termination of unused pins

Table 5. Termination of unused pins

[1] I = Input, IA = Inactive (no pull-up/pull-down enabled), PU = Pull-Up enabled, F = Floating

6.2.2 Pin states in different power modes

Table 6. Pin states in different power modes

[1] Default and programmed pin states are retained in sleep and deep-sleep.

[2] If VBAT> VDD, the external reset pin must be floating to prevent high VBAT leakage.

7. Functional description

7.1 Architectural overview

The ARM Cortex-M4 includes three AHB-Lite buses: the system bus, the I-code bus, and the D-code bus. The I-code and D-code core buses allow for concurrent code and data accesses from different slave ports.

The LPC546xx uses a multi-layer AHB matrix to connect the ARM Cortex-M4 buses and other bus masters to peripherals in a flexible manner that optimizes performance by allowing peripherals that are on different slave ports of the matrix to be accessed simultaneously by different bus masters.

7.2 ARM Cortex-M4 processor

The ARM Cortex-M4 is a general purpose, 32-bit microprocessor, which offers high performance and very low power consumption. The ARM Cortex-M4 offers many new features, including a Thumb-2 instruction set, low interrupt latency, hardware multiply and divide, interruptable/continuable multiple load and store instructions, automatic state save and restore for interrupts, tightly integrated interrupt controller with wake-up interrupt controller, and multiple core buses capable of simultaneous accesses.

A 3-stage pipeline is employed so that all parts of the processing and memory systems can operate continuously. Typically, while one instruction is being executed, its successor is being decoded, and a third instruction is being fetched from memory.

7.3 ARM Cortex-M4 integrated Floating Point Unit (FPU)

The FPU fully supports single-precision add, subtract, multiply, divide, multiply and accumulate, and square root operations. It also provides conversions between fixed-point and floating-point data formats, and floating-point constant instructions.

The FPU provides floating-point computation functionality that is compliant with the ANSI/IEEE Std 754-2008, IEEE Standard for Binary Floating-Point Arithmetic, referred to as the IEEE 754 standard.

7.4 Memory Protection Unit (MPU)

The Cortex-M4 includes a Memory Protection Unit (MPU) which can be used to improve the reliability of an embedded system by protecting critical data within the user application.

The MPU allows separating processing tasks by disallowing access to each other's data, disabling access to memory regions, allowing memory regions to be defined as read-only and detecting unexpected memory accesses that could potentially break the system.

The MPU separates the memory into distinct regions and implements protection by preventing disallowed accesses. The MPU supports up to eight regions each of which can be divided into eight subregions. Accesses to memory locations that are not defined in the MPU regions, or not permitted by the region setting, will cause the Memory Management Fault exception to take place.

7.5 Nested Vectored Interrupt Controller (NVIC) for Cortex-M4

The NVIC is an integral part of the Cortex-M4. The tight coupling to the CPU allows for low interrupt latency and efficient processing of late arriving interrupts.

7.5.1 Features

- **•** Controls system exceptions and peripheral interrupts.
- **•** Supports up to 54 vectored interrupts.
- **•** Eight programmable interrupt priority levels, with hardware priority level masking.
- **•** Relocatable vector table.
- **•** Non-Maskable Interrupt (NMI).
- **•** Software interrupt generation.

7.5.2 Interrupt sources

Each peripheral device has one interrupt line connected to the NVIC but may have several interrupt flags.

7.6 System Tick timer (SysTick)

The ARM Cortex-M4 includes a system tick timer (SysTick) that is intended to generate a dedicated SYSTICK exception. The clock source for the SysTick can be the FRO or the Cortex-M4 core clock.

7.7 On-chip static RAM

The LPC546xx support 200 kB SRAM with separate bus master access for higher throughput and individual power control for low-power operation.

7.8 On-chip flash

The LPC546xx supports up to 512 kB of on-chip flash memory.

7.9 On-chip ROM

The 64 kB on-chip ROM contains the boot loader and the following Application Programming Interfaces (API):

- **•** Flash In-Application Programming (IAP) and In-System Programming (ISP).
- **•** ROM-based USB drivers (HID, CDC, MSC, and DFU). Supports flash updates via USB.
- **•** Supports booting from valid user code in flash, USART, SPI, and I2C.
- **•** Legacy, Single, and Dual image boot.
- **•** OTP API for programming OTP memory.
- **•** Random Number Generator (RNG) API.

7.10 EEPROM

The LPC546xx contains up to 16 kB byte of on-chip word-erasable and word-programmable EEPROM data memory. EEPROM is not accessible in deep-sleep and deep-power-down modes.

7.11 Memory mapping

The LPC546xx incorporates several distinct memory regions. The APB peripheral area is 512 kB in size and is divided to allow for up to 32 peripherals.Each peripheral is allocated 4 kB of space simplifying the address decoding. The registers incorporated into the CPU, such as NVIC, SysTick, and sleep mode control, are located on the private peripheral bus.

The ARM Cortex-M4 processor has a single 4 GB address space. The following table shows how this space is used on the LPC546xx.

Table 7. Memory usage and details

Table 7. Memory usage and details *…continued*

[1] Can be up to 256 MB, upper address 0x8FFF FFFF, if the address shift mode is enabled. See the EMCSYSCTRL register bit 0 in the *UM10912* LPC546xx *user manual*.

[2] Can be up to 128 MB, upper address 0x97FF FFFF, if the address shift mode is enabled. See the EMCSYSCTRL register bit 0 in the *UM10912* LPC546xx *user manual*.

[Figure 9](#page-58-0) shows the overall map of the entire address space from the user program viewpoint following reset.

aaa-029365

APB bridge 0

APB bridge 1

Asynchronous APB bridge

aaa-023944

Fig 10. LPC546xx APB Memory map

7.12 System control

7.12.1 Clock sources

The LPC546xx supports one external and two internal clock sources:

- **•** Free Running Oscillator (FRO).
- **•** Watchdog oscillator (WDOSC).
- **•** Crystal oscillator.

7.12.1.1 Free Running Oscillator (FRO)

The FRO 12 MHz oscillator provides the default clock at reset and provides a clean system clock shortly after the supply pins reach operating voltage.

- **•** 12 MHz internal FRO oscillator, factory trimmed for accuracy, that can optionally be used as a system clock as well as other purposes.
- **•** Selectable 48 MHz or 96 MHz FRO oscillator, factory trimmed for accuracy, that can optionally be used as a system clock as well as other purposes.

7.12.1.2 Watchdog oscillator (WDOSC)

The watchdog oscillator is a low-power internal oscillator. The WDOSC can be used to provide a clock to the WWDT and to the entire chip. The low-power watchdog oscillator provides a selectable frequency in the range of 6 kHz to 1.5 MHz. The accuracy of this clock is limited to \pm 40% over temperature, voltage, and silicon processing variations.

7.12.1.3 Crystal oscillator

The LPC546xx include four independent oscillators. These are the main oscillator, the FRO, the watchdog oscillator, and the RTC oscillator.

Following reset, the LPC546xx will operate from the Internal FRO until switched by software. This allows systems to operate without any external crystal and the boot loader code to operate at a known frequency. See [Figure 11](#page-61-0) and [Figure 12](#page-62-0) for an overview of the LPC546xx clock generation.

7.12.2 System PLL (PLL0)

The system PLL accepts an input clock frequency in the range of 32.768 kHz to 25 MHz. The input frequency is multiplied up to a high frequency with a Current Controlled Oscillator (CCO).

The PLL can be enabled or disabled by software.

7.12.3 USB PLL (PLL1)

The USB PLL accepts an input clock frequency in the range of 1 MHz to 25 MHz. The input frequency is multiplied up to a high frequency with a Current Controlled Oscillator (CCO).

The PLL can be enabled or disabled by software.

7.12.4 Audio PLL (PLL2)

The audio PLL accepts an input clock frequency in the range of 1 MHz to 25 MHz. The input frequency is multiplied up to a high frequency with a Current Controlled Oscillator (CCO).

The PLL can be enabled or disabled by software.

7.12.5 Clock Generation

7.12.6 Brownout detection

The LPC546xx includes a monitor for the voltage level on the V_{DD} pin. If this voltage falls below a fixed level, the BOD sets a flag that can be polled or cause an interrupt. In addition, a separate threshold level can be selected to cause chip reset.

7.12.7 Safety

The LPC546xx includes a Windowed WatchDog Timer (WWDT), which can be enabled by software after reset. Once enabled, the WWDT remains locked and cannot be modified in any way until a reset occurs.

7.13 Code security (enhanced Code Read Protection - eCRP)

eCRP is a mechanism that allows the user to enable different features in the security system. The features are specified using a combination of OTP and flash values. Some levels are only controlled by either flash or OTP, but the majority have dual control. The overlap allows higher security by specifying access using OTP bits, which cannot be changed (except to increase security) while allowing customers who are less concerned about security the ability to change levels in the flash image.

eCRP is calculated by reading the ECRP from the flash boot sector (offset 0x0000 0020) and then masking it with the value read from OTP. The OTP bits are more restrictive (that is, disable access) than equivalent values in flash. Certain aspects of eCRP are only specified in the OTP (that is, Mass Erase disable), while others are only specified in flash (that is, Sector Protection count).

For Dual Enhanced images, eCRP is calculated by reading the eCRP from the bootable image sector. The bootable image is defined as the highest revision image that passes the required validation methods.

Remark: If the ECRP is set to the most restrictive combination of OTP and the ECRP of the images, no future factory testing can be performed on the device.

7.14 Power control

The LPC546xx support a variety of power control features. In Active mode, when the chip is running, power and clocks to selected peripherals can be adjusted for power consumption. In addition, there are three special modes of processor power reduction with different peripherals running: sleep mode, deep-sleep mode, and deep power-down mode that can be activated using the power API library from the LPCOpen software package.

7.14.1 Sleep mode

In sleep mode, the system clock to the CPU is stopped and execution of instructions is suspended until either a reset or an interrupt occurs. Peripheral functions, if selected to be clocked can continue operation during Sleep mode and may generate interrupts to cause the processor to resume execution. Sleep mode eliminates dynamic power used by the processor itself, memory systems and related controllers, internal buses, and unused peripherals. The processor state and registers, peripheral registers, and internal SRAM values are maintained, and the logic levels of the pins remain static.

7.14.2 Deep-sleep mode

In deep-sleep mode, the system clock to the processor is disabled as in sleep mode. All analog blocks are powered down by default but can be selected to keep running through the power API if needed as wake-up sources. The main clock and all peripheral clocks are disabled by default. The flash memory is put in standby mode.

Deep-sleep mode eliminates all power used by analog peripherals and all dynamic power used by the processor itself, memory systems and related controllers, and internal buses. The processor state and registers, peripheral registers, and internal SRAM values are maintained, and the logic levels of the pins remain static.

GPIO Pin Interrupts, GPIO Group Interrupts, and selected peripherals such as USB0, USB1, DMIC, SPI, I2C, USART, WWDT, RTC, Micro-tick Timer, and BOD can be left running in deep sleep mode The FRO, RTC oscillator, and the watchdog oscillator can be left running.In some cases, DMA can operate in deep-sleep mode. For more details, see UM10912, LPC546xx. user manual.

7.14.3 Deep power-down mode

In deep power-down mode, power is shut off to the entire chip except for the RTC power domain and the RESET pin. The LPC546xx can wake up from deep power-down mode via the RESET pin and the RTC alarm. The ALARM1HZ flag in RTC control register generates an RTC wake-up interrupt request, which can wake up the part. During deep power-down mode, the contents of the SRAM and registers are not retained. All functional pins are tri-stated in deep power-down mode.

[Table 8](#page-64-0) shows the peripheral configuration in reduced power modes.

Table 8. Peripheral configuration in reduced power modes

[Table 9](#page-65-0) shows wake-up sources for reduced power modes.

Table 9. Wake-up sources for reduced power modes

	Power mode Wake-up source	Conditions				
Sleep	Any interrupt	Enable interrupt in NVIC.				
	HWWAKE	Certain Flexcomm Interface and DMIC subsystem activity.				
Deep-sleep	Pin interrupts	Enable pin interrupts in NVIC and STARTER0 and/or STARTER1 registers.				
	BOD interrupt	Enable interrupt in NVIC and STARTER0 registers. ٠				
		Enable interrupt in BODCTRL register. ٠				
		Configure the BOD to keep running in this mode with the power API. ٠				
	BOD reset	Enable reset in BODCTRL register.				
	Watchdog interrupt	Enable the watchdog oscillator in the PDRUNCFG0 register.				
		Enable the watchdog interrupt in NVIC and STARTER0 registers. ٠				
		Enable the watchdog in the WWDT MOD register and feed.				
		Enable interrupt in WWDT MOD register.				
		Configure the WDTOSC to keep running in this mode with the power API. ٠				
	Watchdog reset	Enable the watchdog oscillator in the PDRUNCFG0 register. ٠				
		Enable the watchdog and watchdog reset in the WWDT MOD register and feed. ٠				
	Reset pin	Always available.				
	RTC 1 Hz alarm timer	Enable the RTC 1 Hz oscillator in the RTCOSCCTRL register. ٠				
		Enable the RTC bus clock in the AHBCLKCTRL0 register. ٠				
		Start RTC alarm timer by writing a time-out value to the RTC COUNT register. ٠				
		Enable the RTCALARM interrupt in the STARTER0 register. ٠				
	RTC 1 kHz timer time-out and alarm	Enable the RTC 1 Hz oscillator and the RTC 1 kHz oscillator in the RTC CTRL ٠ register.				
		Start RTC 1 kHz timer by writing a value to the WAKE register of the RTC. ٠				
		Enable the RTC wake-up interrupt in the STARTER0 register. ٠				
	Micro-tick timer	Enable the watchdog oscillator in the PDRUNCFG0 register. ٠				
	(intended for ultra-low power wake-up from	Enable the Micro-tick timer clock by writing to the AHBCLKCTRL1 register. ٠				
	deep-sleep mode	Start the Micro-tick timer by writing UTICK CTRL register. ٠				
		Enable the Micro-tick timer interrupt in the STARTER0 register. ٠				
	I2C interrupt	Interrupt from I2C in slave mode.				
	SPI interrupt	Interrupt from SPI in slave mode.				
	USART interrupt	Interrupt from USART in slave or 32 kHz mode.				
	USB0 need clock interrupt	Interrupt from USB0 when activity is detected that requires a clock.				
	USB1 need clock interrupt	Interrupt from USB1 when activity is detected that requires a clock.				
	Ethernet interrupt	Interrupt from ethernet.				
	DMA interrupt	Interrupt from DMA.				
	HWWAKE	Certain Flexcomm Interface and DMIC subsystem activity.				

Table 9. Wake-up sources for reduced power modes

7.15 General Purpose I/O (GPIO)

The LPC546xx provides six GPIO ports with a total of up to 171 GPIO pins.

Device pins that are not connected to a specific peripheral function are controlled by the GPIO registers. Pins may be dynamically configured as inputs or outputs. Separate registers allow setting or clearing any number of outputs simultaneously. The current level of a port pin can be read back no matter what peripheral is selected for that pin.

7.15.1 Features

- **•** Accelerated GPIO functions:
	- **–** GPIO registers are located on the AHB so that the fastest possible I/O timing can be achieved.
	- **–** Mask registers allow treating sets of port bits as a group, leaving other bits unchanged.
	- **–** All GPIO registers are byte and half-word addressable.
	- **–** Entire port value can be written in one instruction.
- **•** Bit-level set and clear registers allow a single instruction set or clear of any number of bits in one port.
- **•** Direction control of individual bits.
- **•** All I/O default to inputs after reset.
- **•** All GPIO pins can be selected to create an edge or level-sensitive GPIO interrupt request.
- **•** One GPIO group interrupt can be triggered by a combination of any pin or pins.

7.16 Pin interrupt/pattern engine

The pin interrupt block configures up to eight pins from all digital pins for providing eight external interrupts connected to the NVIC. The pattern match engine can be used in conjunction with software to create complex state machines based on pin inputs. Any digital pin, independent of the function selected through the switch matrix can be configured through the SYSCON block as an input to the pin interrupt or pattern match engine. The registers that control the pin interrupt or pattern match engine are located on the I/O+ bus for fast single-cycle access.

7.16.1 Features

- **•** Pin interrupts:
	- **–** Up to eight pins can be selected from all GPIO pins on ports 0 and 1 as edge-sensitive or level-sensitive interrupt requests. Each request creates a separate interrupt in the NVIC.
	- **–** Edge-sensitive interrupt pins can interrupt on rising or falling edges or both.
	- **–** Level-sensitive interrupt pins can be HIGH-active or LOW-active.
	- **–** Level-sensitive interrupt pins can be HIGH-active or LOW-active.
	- **–** Pin interrupts can wake up the device from sleep mode and deep-sleep mode.
- **•** Pattern match engine:
	- **–** Up to eight pins can be selected from all digital pins on ports 0 and 1 to contribute to a boolean expression. The boolean expression consists of specified levels and/or transitions on various combinations of these pins.
	- **–** Each bit slice minterm (product term) comprising of the specified boolean expression can generate its own, dedicated interrupt request.
	- **–** Any occurrence of a pattern match can also be programmed to generate an RXEV notification to the CPU. The RXEV signal can be connected to a pin.
	- **–** Pattern match can be used in conjunction with software to create complex state machines based on pin inputs.
	- **–** Pattern match engine facilities wake-up only from active and sleep modes.

7.17 Serial peripherals

7.17.1 Full-speed USB Host/Device interface (USB0)

The Universal Serial Bus (USB) is a 4-wire bus that supports communication between a host and one or more (up to 127) peripherals. The host controller allocates the USB bandwidth to attached devices through a token-based protocol. The bus supports hot plugging and dynamic configuration of the devices. All transactions are initiated by the host controller.

7.17.1.1 USB0 device controller

The device controller enables 12 Mbit/s data exchange with a USB host controller. It consists of a register interface, serial interface engine, endpoint buffer memory. The serial interface engine decodes the USB data stream and writes data to the appropriate endpoint buffer. The status of a completed USB transfer or error condition is indicated via status registers. An interrupt is also generated if enabled.

Features

- **•** Supports 10 physical (5 logical) endpoints including two control endpoints.
- **•** Single and double-buffering supported.
- **•** Each non-control endpoint supports bulk, interrupt, or isochronous endpoint types.
- **•** Supports wake-up from reduced power mode on USB activity and remote wake-up.
- **•** Supports SoftConnect.
- **•** Link Power Management (LPM) supported.

7.17.1.2 USB0 host controller

The host controller enables full- and low-speed data exchange with USB devices attached to the bus. It consists of register interface, serial interface engine and DMA controller. The register interface complies with the Open Host Controller Interface (OHCI) specification.

Features

- **•** OHCI compliant.
- **•** Two downstream ports.

7.17.2 High-speed USB Host/Device interface (USB1)

The Universal Serial Bus (USB) is a 4-wire bus that supports communication between a host and one or more (up to 127) peripherals. The host controller allocates the USB bandwidth to attached devices through a token-based protocol. The bus supports hot plugging and dynamic configuration of the devices. All transactions are initiated by the host controller.

7.17.2.1 USB1 device controller

The device controller enables 480 Mbit/s data exchange with a USB host controller. It consists of a register interface, serial interface engine, endpoint buffer memory. The serial interface engine decodes the USB data stream and writes data to the appropriate endpoint buffer. The status of a completed USB transfer or error condition is indicated via status registers. An interrupt is also generated if enabled.

Features

- **•** Fully compliant with *USB 2.0 Specification* (high speed).
- **•** Supports 8 physical (16 logical) endpoints with up to 8 kB endpoint buffer RAM.
- **•** Supports Control, Bulk, Interrupt and Isochronous endpoints.
- **•** Scalable realization of endpoints at run time.
- **•** Endpoint Maximum packet size selection (up to USB maximum specification) by software at run time.
- **•** While USB is in the Suspend mode, the LPC546xx can enter one of the reduced power modes and wake up on USB activity.
- **•** Double buffer implementation for Bulk and Isochronous endpoints.

7.17.2.2 USB1 host controller

The host controller enables high speed data exchange with USB devices attached to the bus. It consists of register interface and serial interface engine. The register interface complies with the Enhanced Host Controller Interface (EHCI) specification.

Features

- **•** EHCI compliant.
- **•** Two downstream ports.
- **•** Supports per-port power switching.

7.17.3 Ethernet AVB

The Ethernet block enables a host to transmit and receive data over Ethernet in compliance with the IEEE 802.3-2008 standard. The Ethernet interface contains a full featured 10 Mbps or 100 Mbps Ethernet MAC (Media Access Controller) designed to provide optimized performance through the use of DMA hardware acceleration.

7.17.3.1 Features

- **•** 10/100 Mbit/s
- **•** DMA support
- **•** Power management remote wake-up frame and magic packet detection
- **•** Supports both full-duplex and half-duplex operation
	- **–** Supports CSMA/CD Protocol for half-duplex operation.
	- **–** Supports IEEE 802.3x flow control for full-duplex operation.
	- **–** Optional forwarding of received pause control frames to the user application in full-duplex operation.
	- **–** Supports IEEE 802.1AS-2011 and 802.1-Qav-2009 for Audio Video (AV) traffic.
	- **–** Software support for AVB feature is available from NXP Professional Services. See nxp.com for more details.
	- **–** Back-pressure support for half-duplex operation.
	- **–** Automatic transmission of zero-quanta pause frame on deassertion of flow control input in full-duplex operation.
- **•** Supports IEEE1588 time stamping and IEEE 1588 advanced time stamping (IEEE 1588-2008 v2).

7.17.4 SPI Flash Interface (SPIFI)

The SPI Flash Interface allows low-cost serial flash memories to be connected to the LPC546xx microcontroller with little performance penalty compared to parallel flash devices with higher pin count.

After a few commands configure the interface at startup, the entire flash content is accessible as normal memory using byte, halfword, and word accesses by the processor and/or DMA channels. Simple sequences of commands handle erasure and programming.

Many serial flash devices use a half-duplex command-driven SPI protocol for device setup and initialization and then move to a half-duplex, command-driven 4-bit protocol for normal operation. Different serial flash vendors and devices accept or require different commands and command formats. SPIFI provides sufficient flexibility to be compatible with common flash devices and includes extensions to help insure compatibility with future devices.

7.17.4.1 Features

- **•** Interfaces to serial flash memory in the main memory map.
- **•** Supports classic and 4-bit bidirectional serial protocols.
- **•** Half-duplex protocol compatible with various vendors and devices.
- **•** Quad SPI Flash Interface with 1-, 2-, or 4-bit data at rates of up to 52 MB per second.

- **•** Supports DMA access.
- **•** Provides XIP (execute in place) feature to execute code directly from serial flash.

7.17.5 CAN Flexible Data (CAN FD) interface

The LPC546xx contains two CAN FD interfaces, CAN FD 1 and CAN FD 2.

7.17.5.1 Features

- **•** Conforms with CAN protocol version 2.0 part A, B and ISO 11898-1.
- **•** CAN FD with up to 64 data bytes supported.
- **•** CAN Error Logging.
- **•** AUTOSAR support.
- **•** SAE J1939 support.
- **•** Improved acceptance filtering.

7.17.6 DMIC subsystem

7.17.6.1 Features

- **•** Pulse-Density Modulation (PDM) data input for left and/or right channels on 1 or 2 buses.
- **•** Flexible decimation.
- **•** 16 entry FIFO for each channel.
- **•** DC blocking or unaltered DC bias can be selected.
- **•** Data can be transferred using DMA from deep-sleep mode without waking up the CPU, then automatically returning to deep-sleep mode.
- **•** Data can be streamed directly to I2S on Flexcomm Interface 7.

7.17.7 Smart card interface

7.17.7.1 Features

- **•** Two DMA supported ISO 7816 Smart Card Interfaces.
- **•** Both asynchronous protocols, T = 0 and T = 1 are supported.

7.17.8 Flexcomm Interface serial communication

7.17.8.1 Features

- **•** USART with asynchronous operation or synchronous master or slave operation.
- **•** SPI master or slave, with up to 4 slave selects.
- **•** I ²C, including separate master, slave, and monitor functions.
- **•** Two I2S functions using Flexcomm Interface 6 and Flexcomm Interface 7.
- **•** Data for USART, SPI, and I2S traffic uses the Flexcomm Interface FIFO. The I2C function does not use the FIFO.

7.17.8.2 SPI serial I/O controller

Features

- **•** Maximum data rates of 48 Mbit/s in master mode and 14 Mbit/s in slave mode for SPI functions.
- **•** Data frames of 1 to 16 bits supported directly. Larger frames supported by software or DMA set-up.
- **•** Master and slave operation.
- **•** Data can be transmitted to a slave without the need to read incoming data. This can be useful while setting up an SPI memory.
- **•** Control information can optionally be written along with data. This allows very versatile operation, including "any length" frames.
- **•** Four Slave Select input/outputs with selectable polarity and flexible usage.
- **•** Activity on the SPI in slave mode allows wake-up from deep-sleep mode on any enabled interrupt.

Remark: Texas Instruments SSI and National Microwire modes are not supported.

7.17.8.3 I2C-bus interface

The I²C-bus is bidirectional for inter-IC control using only two wires: a serial clock line (SCL) and a serial data line (SDA). Each device is recognized by a unique address and can operate as either a receiver-only device (for example, an LCD driver) or a transmitter with the capability to both receive and send information (such as memory). Transmitters and/or receivers can operate in either master or slave mode, depending on whether the chip has to initiate a data transfer or is only addressed. The I^2C is a multi-master bus and can be controlled by more than one bus master connected to it.

Features

- **•** All I2Cs support standard, Fast-mode, and Fast-mode Plus with data rates of up to 1 Mbit/s.
- **•** All I2Cs support high-speed slave mode with data rates of up to 3.4 Mbit/s.
- **•** Independent Master, Slave, and Monitor functions.
- **•** Supports both Multi-master and Multi-master with Slave functions.
- **•** Multiple I2C slave addresses supported in hardware.
- **•** One slave address can be selectively qualified with a bit mask or an address range in order to respond to multiple I²C-bus addresses.
- **•** 10-bit addressing supported with software assist.
- **•** Supports SMBus.
- **•** Activity on the I2C in slave mode allows wake-up from deep-sleep mode on any enabled interrupt.
7.17.8.4 USART

Features

- **•** Maximum bit rates of 6.25 Mbit/s in asynchronous mode.
- **•** The maximum supported bit rate for USART master synchronous mode is 24 Mbit/s, and the maximum supported bit rate for USART slave synchronous mode is 12.5 Mbit/s.
- **•** 7, 8, or 9 data bits and 1 or 2 stop bits.
- **•** Synchronous mode with master or slave operation. Includes data phase selection and continuous clock option.
- **•** Multiprocessor/multidrop (9-bit) mode with software address compare.
- **•** RS-485 transceiver output enable.
- **•** Autobaud mode for automatic baud rate detection
- **•** Parity generation and checking: odd, even, or none.
- **•** Software selectable oversampling from 5 to 16 clocks in asynchronous mode.
- **•** One transmit and one receive data buffer.
- **•** RTS/CTS for hardware signaling for automatic flow control. Software flow control can be performed using Delta CTS detect, Transmit Disable control, and any GPIO as an RTS output.
- **•** Received data and status can optionally be read from a single register
- **•** Break generation and detection.
- **•** Receive data is 2 of 3 sample "voting". Status flag set when one sample differs.
- **•** Built-in Baud Rate Generator with auto-baud function.
- **•** A fractional rate divider is shared among all USARTs.
- **•** Interrupts available for Receiver Ready, Transmitter Ready, Receiver Idle, change in receiver break detect, Framing error, Parity error, Overrun, Underrun, Delta CTS detect, and receiver sample noise detected.
- **•** Loopback mode for testing of data and flow control.
- **•** In synchronous slave mode, wakes up the part from deep-sleep mode.
- **•** Special operating mode allows operation at up to 9600 baud using the 32.768 kHz RTC oscillator as the UART clock. This mode can be used while the device is in deep-sleep mode and can wake-up the device when a character is received.
- **•** USART transmit and receive functions work with the system DMA controller.

7.17.8.5 I2S-bus interface

The I2S bus provides a standard communication interface for streaming data transfer applications such as digital audio or data collection. The I2S bus specification defines a 3-wire serial bus, having one data, one clock, and one word select/frame trigger signal, providing single or dual (mono or stereo) audio data transfer as well as other configurations. In the LPC546xx, the I2S function is included in Flexcomm Interface 6 and Flexcomm Interface 7. Each of the Flexcomm Interface implements four I²S channel pairs.

The I2S interface within one Flexcomm Interface provides at least one channel pair that can be configured as a master or a slave. Other channel pairs, if present, always operate as slaves. All of the channel pairs within one Flexcomm Interface share one set of I2S

signals, and are configured together for either transmit or receive operation, using the same mode, same data configuration and frame configuration. All such channel pairs can participate in a time division multiplexing (TDM) arrangement. For cases requiring an MCLK input and/or output, this is handled outside of the I²S block in the system level clocking scheme.

Features

- **•** A Flexcomm Interface may implement one or more I2S channel pairs, the first of which could be a master or a slave, and the rest of which would be slaves. All channel pairs are configured together for either transmit or receive and other shared attributes. The number of channel pairs is defined for each Flexcomm Interface, and may be from 0 to 4.
- **•** Configurable data size for all channels within one Flexcomm Interface, from 4 bits to 32 bits. Each channel pair can also be configured independently to act as a single channel (mono as opposed to stereo operation).
- **•** All channel pairs within one Flexcomm Interface share a single bit clock (SCK) and word select/frame trigger (WS), and data line (SDA).
- **•** Data for all I2S traffic within one Flexcomm Interface uses the Flexcomm Interface FIFO. The FIFO depth is 8 entries.
- **•** Left justified and right justified data modes.
- **•** DMA support using FIFO level triggering.
- **•** TDM (Time Division Multiplexing) with a several stereo slots and/or mono slots is supported. Each channel pair can act as any data slot. Multiple channel pairs can participate as different slots on one TDM data line.
- **•** The bit clock and WS can be selectively inverted.
- **•** Sampling frequencies supported depends on the specific device configuration and applications constraints (for example, system clock frequency and PLL availability.) but generally supports standard audio data rates. See the data rates section in I²S chapter in the LPC546xx. user manual to calculate clock and sample rates.

Remark: The Flexcomm Interface function clock frequency should not be above 48 MHz.

7.18 Digital peripheral

7.18.1 LCD controller

The LCD controller provides all of the necessary control signals to interface directly to various color and monochrome LCD panels. Both STN (single and dual panel) and TFT panels can be operated. The display resolution is selectable and can be up to 1024×768 pixels. Several color modes are provided, up to a 24-bit true-color non-palettized mode. An on-chip 512 byte color palette allows reducing bus utilization (that is, memory size of the displayed data) while still supporting many colors.

The LCD interface includes its own DMA controller to allow it to operate independently of the CPU and other system functions. A built-in FIFO acts as a buffer for display data, providing flexibility for system timing. Hardware cursor support can further reduce the amount of CPU time required to operate the display.

7.18.1.1 Features

- **•** AHB master interface to access frame buffer.
- **•** Setup and control via a separate AHB slave interface.
- **•** Dual 16-deep programmable 64-bit wide FIFOs for buffering incoming display data.
- **•** Supports single and dual-panel monochrome Super Twisted Nematic (STN) displays with 4-bit or 8-bit interfaces.
- **•** Supports single and dual-panel color STN displays.
- **•** Supports Thin Film Transistor (TFT) color displays.
- Programmable display resolution including, but not limited to: 320×200 , 320×240 , 640×200 , 640×240 , 640×480 , 800×600 , and 1024×768 .
- **•** Hardware cursor support for single-panel displays.
- **•** 15 gray-level monochrome, 3375 color STN, and 32 K color palettized TFT support.
- **•** 1, 2, or 4 bits-per-pixel (bpp) palettized displays for monochrome STN.
- **•** 1, 2, 4, or 8 bpp palettized color displays for color STN and TFT.
- **•** 16 bpp true-color non-palettized for color STN and TFT.
- **•** 24 bpp true-color non-palettized for color TFT.
- **•** Programmable timing for different display panels.
- 256 entry, 16-bit palette RAM, arranged as a 128 x 32-bit RAM.
- **•** Frame, line, and pixel clock signals.
- **•** AC bias signal for STN, data enable signal for TFT panels.
- **•** Supports little and big-endian, and Windows CE data formats.
- **•** LCD panel clock may be generated from the peripheral clock, or from a clock input pin.

7.18.2 SD/MMC card interface

The SD/MMC card interface supports the following modes to control:

7.18.2.1 Features

- **•** Secure Digital memory (SD version 1.1).
- **•** Secure Digital I/O (SDIO version 2.0).
- **•** Consumer Electronics Advanced Transport Architecture (CE-ATA version 1.1).
- **•** MultiMedia Cards (MMC version 4.1).
- **•** Supports up to a maximum of 50 MHz of interface frequency.

7.18.3 External memory controller

The LPC546xx EMC is an ARM PrimeCell MultiPort Memory Controller peripheral offering support for asynchronous static memory devices such as RAM, ROM, and flash. In addition, it can be used as an interface with off-chip memory-mapped devices and peripherals. The EMC is an Advanced Microcontroller Bus Architecture (AMBA) compliant peripheral.

7.18.3.1 Features

- **•** Read and write buffers to reduce latency and to improve performance.
- **•** Low transaction latency.
- **•** Asynchronous static memory device support including RAM, ROM, and flash, with or without asynchronous page mode.
- **•** 8/16/32 data and 16/20/26 address lines wide static memory support.
- **•** Static memory features include:
	- **–** Asynchronous page mode read.
	- **–** Programmable Wait States.
	- **–** Bus turnaround delay.
	- **–** Output enable and write enable delays.
	- **–** Extended wait.
- **•** Dynamic memory interface support including single data rate SDRAM.
- **•** 16 bit and 32 bit wide chip select SDRAM memory support.
- **•** EMC bus width (bit) on LQFP100 and TFBGA100 packages supports up to 8/16 data line wide static memory, in addition to dynamic memories, such as, SDRAM (2 banks only) with an SDRAM clock of up to 100 MHz.
- **•** Four chip selects for synchronous memory and four chip selects for static memory devices.
- **•** Power-saving modes dynamically control EMC_CKE and EMC_CLK outputs to SDRAMs.
- **•** Dynamic memory self-refresh mode controlled by software.
- **•** Controller supports 2048 (A0 to A10), 4096 (A0 to A11), and 8192 (A0 to A12) row address synchronous memory parts. That is typical 512 MB, 256 MB, and 128 MB parts, with 4, 8, 16, or 32 data bits per device.
- **•** Separate reset domains allow the for auto-refresh through a chip reset if desired.

Note: Synchronous static memory devices (synchronous burst mode) are not supported.

7.18.4 DMA controller

The DMA controller allows peripheral-to memory, memory-to-peripheral, and memory-to-memory transactions. Each DMA stream provides unidirectional DMA transfers for a single source and destination.

7.18.4.1 Features

- **•** One channel per on-chip peripheral direction: typically one for input and one for output for most peripherals.
- **•** DMA operations can optionally be triggered by on- or off-chip events.
- **•** Priority is user selectable for each channel.
- **•** Continuous priority arbitration.
- **•** Address cache.
- **•** Efficient use of data bus.
- **•** Supports single transfers up to 1,024 words.
- **•** Address increment options allow packing and/or unpacking data.

7.19 Counter/timers

7.19.1 General-purpose 32-bit timers/external event counter

The LPC546xx includes five general-purpose 32-bit timer/counters.

The timer/counter is designed to count cycles of the system derived clock or an externally-supplied clock. It can optionally generate interrupts, generate timed DMA requests, or perform other actions at specified timer values, based on four match registers. Each timer/counter also includes two capture inputs to trap the timer value when an input signal transitions, optionally generating an interrupt.

7.19.1.1 Features

- **•** A 32-bit timer/counter with a programmable 32-bit prescaler.
- **•** Counter or timer operation.
- **•** Up to four 32-bit captures can take a snapshot of the timer value when an input signal transitions. A capture event may also optionally generate an interrupt. The number of capture inputs for each timer that are actually available on device pins may vary by device.
- **•** Four 32-bit match registers that allow:
	- **–** Continuous operation with optional interrupt generation on match.
	- **–** Stop timer on match with optional interrupt generation.
	- **–** Reset timer on match with optional interrupt generation.
	- **–** Shadow registers are added for glitch-free PWM output.
- **•** For each timer, up to four external outputs corresponding to match registers with the following capabilities (the number of match outputs for each timer that are actually available on device pins may vary by device):
	- **–** Set LOW on match.
	- **–** Set HIGH on match.

- **–** Toggle on match.
- **–** Do nothing on match.
- **•** Up to two match registers can be used to generate timed DMA requests.
- **•** The timer and prescaler may be configured to be cleared on a designated capture event. This feature permits easy pulse width measurement by clearing the timer on the leading edge of an input pulse and capturing the timer value on the trailing edge.
- **•** Up to four match registers can be configured for PWM operation, allowing up to three single edged controlled PWM outputs. (The number of match outputs for each timer that are actually available on device pins may vary by device.)

7.19.2 SCTimer/PWM

The SCTimer/PWM allows a wide variety of timing, counting, output modulation, and input capture operations. The inputs and outputs of the SCTimer/PWM are shared with the capture and match inputs/outputs of the 32-bit general-purpose counter/timers.

The SCTimer/PWM can be configured as two 16-bit counters or a unified 32-bit counter. In the two-counter case, in addition to the counter value the following operational elements are independent for each half:

- **•** State variable.
- **•** Limit, halt, stop, and start conditions.
- **•** Values of Match/Capture registers, plus reload or capture control values.

In the two-counter case, the following operational elements are global to the SCTimer/PWM, but the last three can use match conditions from either counter:

- **•** Clock selection
- **•** Inputs
- **•** Events
- **•** Outputs
- **•** Interrupts

7.19.2.1 Features

- **•** Two 16-bit counters or one 32-bit counter.
- **•** Counter(s) clocked by bus clock or selected input.
- **•** Up counter(s) or up-down counter(s).
- **•** State variable allows sequencing across multiple counter cycles.
- **•** Event combines input or output condition and/or counter match in a specified state.
- **•** Events control outputs, interrupts, and the SCTimer/PWM states.
	- **–** Match register 0 can be used as an automatic limit.
	- **–** In bi-directional mode, events can be enabled based on the count direction.
	- **–** Match events can be held until another qualifying event occurs.
- **•** Selected event(s) can limit, halt, start, or stop a counter.
- **•** Supports:

- **–** 8 inputs
- **–** 10 outputs
- **–** 10 match/capture registers
- **–** 10 events
- **–** 10 states
- **•** PWM capabilities including dead time and emergency abort functions

7.19.3 Windowed WatchDog Timer (WWDT)

The purpose of the watchdog is to reset the controller if software fails to periodically service it within a programmable time window.

7.19.3.1 Features

- **•** Internally resets chip if not periodically reloaded during the programmable time-out period.
- **•** Optional windowed operation requires reload to occur between a minimum and maximum time period, both programmable.
- **•** Optional warning interrupt can be generated at a programmable time prior to watchdog time-out.
- **•** Enabled by software but requires a hardware reset or a watchdog reset/interrupt to be disabled.
- **•** Incorrect feed sequence causes reset or interrupt if enabled.
- **•** Flag to indicate watchdog reset.
- **•** Programmable 24-bit timer with internal prescaler.
- Selectable time period from $(T_{cy(WDCLK)} \times 256 \times 4)$ to $(T_{cy(WDCLK)} \times 2^{24} \times 4)$ in multiples of $T_{cy(WDCLK)} \times 4$.
- **•** The Watchdog Clock (WDCLK) uses the WDOSC as the clock source.

7.19.4 Real Time Clock (RTC) timer

The RTC timer is a 32-bit timer which counts down from a preset value to zero. At zero, the preset value is reloaded and the counter continues. The RTC timer uses the 32.768 kHz clock input to create a 1 Hz or 1 kHz clock.

7.19.5 Multi-Rate Timer (MRT)

The Multi-Rate Timer (MRT) provides a repetitive interrupt timer with four channels. Each channel can be programmed with an independent time interval, and each channel operates independently from the other channels.

7.19.5.1 Features

- **•** 24-bit interrupt timer.
- **•** Four channels independently counting down from individually set values.
- **•** Repeat and one-shot interrupt modes.

7.19.6 Repetitive Interrupt Timer (RIT)

The repetitive interrupt timer provides a free-running 48-bit counter which is compared to a selectable value, generating an interrupt when a match occurs. Any bits of the timer/compare can be masked such that they do not contribute to the match detection. The repetitive interrupt timer can be used to create an interrupt that repeats at predetermined intervals.

7.19.6.1 Features

- **•** 48-bit counter running from the main clock. Counter can be free-running or can be reset when an RIT interrupt is generated.
- **•** 48-bit compare value.
- **•** 48-bit compare mask. An interrupt is generated when the counter value equals the compare value, after masking. This allows for combinations not possible with a simple compare.
- **•** Can be used for ETM debug time stamping.

7.20 12-bit Analog-to-Digital Converter (ADC)

The ADC supports a resolution of 12-bit and fast conversion rates of up to 5 Msamples/s. Sequences of analog-to-digital conversions can be triggered by multiple sources. Possible trigger sources are the SCTimer/PWM, external pins, and the ARM TXEV interrupt.

The ADC supports a variable clocking scheme with clocking synchronous to the system clock or independent, asynchronous clocking for high-speed conversions

The ADC includes a hardware threshold compare function with zero-crossing detection. The threshold crossing interrupt is connected internally to the SCTimer/PWM inputs for tight timing control between the ADC and the SCTimer/PWM.

7.20.1 Features

- **•** 12-bit successive approximation analog to digital converter.
- **•** Input multiplexing among up to 12 pins.
- **•** Two configurable conversion sequences with independent triggers.
- Optional automatic high/low threshold comparison and "zero crossing" detection.
- **•** Measurement range VREFN to VREFP (typically 3 V; not to exceed VDDA voltage level).
- **•** 12-bit conversion rate of 5.0 Msamples/s. Options for reduced resolution at higher conversion rates.
- **•** Burst conversion mode for single or multiple inputs.
- **•** Synchronous or asynchronous operation. Asynchronous operation maximizes flexibility in choosing the ADC clock frequency, Synchronous mode minimizes trigger latency and can eliminate uncertainty and jitter in response to a trigger.

7.21 CRC engine

The Cyclic Redundancy Check (CRC) generator with programmable polynomial settings supports several CRC standards commonly used. To save system power and bus bandwidth, the CRC engine supports DMA transfers.

7.21.1 Features

- **•** Supports three common polynomials CRC-CCITT, CRC-16, and CRC-32.
	- **–** CRC-CCITT: x16 + x12 + x5 + 1
	- $-$ CRC-16: $x^{16} + x^{15} + x^2 + 1$
	- $-$ CRC-32: $x^{32} + x^{26} + x^{23} + x^{22} + x^{16} + x^{12} + x^{11} + x^{10} + x^8 + x^7 + x^5 + x^4 + x^2 + x + 1$
- **•** Bit order reverse and 1ís complement programmable setting for input data and CRC sum.
- **•** Programmable seed number setting.
- **•** Supports CPU PIO or DMA back-to-back transfer.
- **•** Accept any size of data width per write: 8, 16 or 32-bit.
	- **–** 8-bit write: 1-cycle operation.
	- **–** 16-bit write: 2-cycle operation (8-bit x 2-cycle).
	- **–** 32-bit write: 4-cycle operation (8-bit x 4-cycle).

7.22 Temperature sensor

The temperature sensor transducer uses an intrinsic pn-junction diode reference and outputs a CTAT voltage (Complement To Absolute Temperature). The output voltage varies inversely with device temperature with an absolute accuracy of better than \pm 5 °C over the full temperature range (-40 °C to +105 °C). The temperature sensor is only approximately linear with a slight curvature. The output voltage is measured over different ranges of temperatures and fit with linear-least-square lines.

After power-up, the temperature sensor output must be allowed to settle to its stable value before it can be used as an accurate ADC input.

For an accurate measurement of the temperature sensor by the ADC, the ADC must be configured in single-channel burst mode. The last value of a nine-conversion (or more) burst provides an accurate result.

7.23 Security features

The OTP memory contains a memory bank of 128 bits each. OTP bank contains 4 words: word 0 for ECRP, word 1 is reserved, words 2 and 3 can be used by user application for storing application specific options.

7.23.1 Features

- **•** OTP memory.
- **•** Random number generator (RNG).

7.23.2 SHA-1 and SHA-2

The Hash peripheral is used to perform SHA-1 and SHA-2 (256) based hashing. A hash takes an arbitrarily large message or image and forms a relatively small fixed size "unique" number called a digest. The data is fed by words from the processor, DMA, or hosted access; the words are converted from little-endian (ARM standard) to big-endian (SHA standard) by the block.

7.23.2.1 Features

- **•** Used with an HMAC to support a challenge/response or to validate a message.
- **•** Can be used to verify external memory that has not been compromised.

7.24 Code security (enhanced Code Read Protection - eCRP)

eCRP is a mechanism that allows the user to enable different features in the security system. The features are specified using a combination of OTP and flash values. Some levels are only controlled by either flash or OTP, but the majority have dual control. The overlap allows higher security by specifying access using OTP bits, which cannot be changed (except to increase security) while allowing customers who are less concerned about security the ability to change levels in the flash image.

eCRP is calculated by reading the ECRP from the flash boot sector (offset 0x0000 0020) and then masking it with the value read from OTP. The OTP bits are more restrictive (that is, disable access) than equivalent values in flash. Certain aspects of eCRP are only specified in the OTP (that is, Mass Erase disable), while others are only specified in flash (that is, Sector Protection count).

For Dual Enhanced images, eCRP is calculated by reading the eCRP from the bootable image sector. The bootable image is defined as the highest revision image that passes the required validation methods.

7.25 Emulation and debugging

Debug and trace functions are integrated into the ARM Cortex-M4. Serial wire debug and trace functions are supported. The ARM Cortex-M4 is configured to support up to eight breakpoints and four watch points.

The ARM SYSREQ reset is supported and causes the processor to reset the peripherals, execute the boot code, restart from address 0x0000 0000, and break at the user entry point.

The SWD pins are multiplexed with other digital I/O pins. On reset, the pins assume the SWD functions by default.

8. Limiting values

Table 10. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).[\[1\]](#page-83-0)

Table 10. Limiting values *…continued*

In accordance with the Absolute Maximum Rating System (IEC 60134).[1]

Symbol	Parameter	Conditions		Min	Max	Unit
$P_{tot (pack)}$	total power dissipation (per package)	LQFP208, based on package heat transfer, not device power consumption	$[11]$		1.2	W
		LQFP208, based on package heat transfer, not device power consumption	$[12]$		0.95	W
		LQFP100, based on package heat transfer, not device power consumption	$[11]$		0.82	W
		LQFP100, based on package heat transfer, not device power consumption	$[12]$		0.60	W
		TFBGA180, based on package heat transfer, not device power consumption	$[11]$		0.95	W
		TFBGA180, based on package heat transfer, not device power consumption	[13]		1.2	W
		TFBGA100, based on package heat transfer, not device power consumption	$[11]$		0.57	W
		TFBGA100, based on package heat transfer, not device power consumption	$[13]$		0.65	W
V _{ESD}	electrostatic discharge voltage	human body model; all pins	$[4]$		2000	V

[1] The following applies to the limiting values:

a) This product includes circuitry specifically designed for the protection of its internal devices from the damaging effects of excessive static charge. Nonetheless, it is suggested that conventional precautions be taken to avoid applying greater than the rated maximum.

- b) Parameters are valid over operating temperature range unless otherwise specified. All voltages are with respect to V_{SS} unless otherwise noted.
- c) The limiting values are stress ratings only and operating the part at these values is not recommended and proper operation is not guaranteed. The conditions for functional operation are specified in [Table 21](#page-95-0).
- [2] Maximum/minimum voltage above the maximum operating voltage (see [Table 21\)](#page-95-0) and below ground that can be applied for a short time (< 10 ms) to a device without leading to irrecoverable failure. Failure includes the loss of reliability and shorter lifetime of the device.
- [3] The peak current is limited to 25 times the corresponding maximum current.
- [4] Human body model: equivalent to discharging a 100 pF capacitor through a 1.5 k Ω series resistor.
- [5] V_{DD} present or not present. Compliant with the I²C-bus standard. 5.5 V can be applied to this pin when V_{DD} is powered down.
- [6] Applies to all 5 V tolerant I/O pins except true open-drain pins.
- [7] Including the voltage on outputs in 3-state mode.
- [8] An ADC input voltage above 3.6 V can be applied for a short time without leading to immediate, unrecoverable failure. Accumulated exposure to elevated voltages at 4.6 V must be less than 10^6 s total over the lifetime of the device. Applying an elevated voltage to the ADC inputs for a long time affects the reliability of the device and reduces its lifetime.
- [9] It is recommended to connect an overvoltage protection diode between the analog input pin and the voltage supply pin.
- [10] Dependent on package type.
- [11] JEDEC (4.5 in \times 4 in); still air.
- [12] Single layer (4.5 in \times 3 in); still air.
- [13] 8-layer (4.5 in \times 3 in); still air.

(1)

9. Thermal characteristics

The average chip junction temperature, T_i (°C), can be calculated using the following equation:

$$
T_j = T_{amb} + (P_D \times R_{th(j-a)})
$$

- T_{amb} = ambient temperature ($°C$),
- $R_{th(i-a)}$ = the package junction-to-ambient thermal resistance (°C/W)
- P_D = sum of internal and I/O power dissipation

The internal power dissipation is the product of I_{DD} and V_{DD} . The I/O power dissipation of the I/O pins is often small and many times can be negligible. However it can be significant in some applications.

Table 11. Thermal resistance

10. Static characteristics

10.1 General operating conditions

Table 12. General operating conditions

Tamb = 40 C to +105 C, unless otherwise specified.

[1] Typical ratings are not guaranteed. The values listed are for room temperature (25 °C), nominal supply voltages.

[2] Attempting to program below 2.7 V will result in unpredictable results and the part might enter an unrecoverable state.

[3] The LPC5460x/61x operates at CPU frequencies of up to 180 MHz. The LPC54628 operates at CPU frequencies of up to 220 MHz.

10.2 Power-up ramp conditions

Table 13. Power-up characteristics[\[1\]](#page-87-0)

- [1] Assert the external reset pin until V_{DD} is > 1.62 V if the power-up characteristic specification cannot be implemented.
- [2] V_{DD} to stay above V_1 for the entire duration t_{wd}.
- [3] V_{DD} to stay below V_2 for the minimum duration of t_{wd}.

10.3 CoreMark data

Table 14. CoreMark score[\[1\]](#page-87-10)

 $T_{amb} = 25^{\circ}C$, $V_{DD} = 3.3V$

[1] Based on the power API library from the SDK software package available on nxp.com.

[2] Clock source FRO. PLL disabled.

- [3] Clock source 12 MHz FRO. PLL enabled.
- [4] Characterized through bench measurements using typical samples.
- [5] Compiler settings: IAR C/C++ Compiler for Arm ver 8.22.2, optimization level 3, optimized for time on.
- [6] See the FLASHCFG register in the LPC546xx. User Manual for system clock flash access time settings. Acceleration enable bit in the FLASHCFG register is set to 1.
- [7] Flash is powered down
- [8] SRAM1, SRAM2, SRAM3, and USB SRAM powered down. SRAM0 and SRAMX powered.
- [9] At 220 MHz the minimum system clock/access time can be lower when compared to 180 MHz because the power library optimizes the on-chip voltage regulator.

10.4 Power consumption

Power measurements in Active, sleep, and deep-sleep modes were performed under the following conditions:

- **•** Configure all pins as GPIO with pull-up resistor disabled in the IOCON block.
- **•** Configure GPIO pins as outputs using the GPIO DIR register.
- **•** Write 1 to the GPIO CLR register to drive the outputs LOW.
- **•** All peripherals disabled.

Symbol	Parameter	Conditions		Min	Typ ^[2]	Max	Unit
Active mode ^[1]							
I_{DD}	supply current	CoreMark code executed from SRAMX; flash powered down					
		$CCLK = 12 MHz$	[3][4][5][7]		3.3		mA
		$CCLK = 96 MHz$	[3][4][5][7]		11		mA
		$CCLK = 180 MHz$	[4][5][7][8]		24		mA
		$CCLK = 220 MHz$	[4][5][7][8]		30		mA
I_{DD}	supply current	CoreMark code executed from flash; CCLK = 12 MHz; 1 system clock flash access time.	[3][4][5][6]		4		mA
		CCLK = 96 MHz; 5 system clock flash access time.	[3][4][5][6]		9.4		mA
		$CCLK = 180 MHz$; 9 system clock flash access time.	[4][5][6][8]		17		mA
		$CCLK = 220 MHz$; 8 system clock flash access time.	[4][5][6][8][9]		22.4		mA
		$CCLK = 220 MHz$; 9 system clock flash access time.	[4][5][6][8]		21.9		m _A
Sleep mode							
I_{DD}	supply current	$CCLK = 12 MHz$	[3][4][5][7]		1.7		mA
		$CCLK = 96 MHz$	[3][4][5][7]		4.1		mA
		$CCLK = 180 MHz$	[4][5][8]		8.3		mA

Table 15. Static characteristics: Power consumption in active and sleep mode $T_{amb} = -40$ $^{\circ}$ C to $+105$ $^{\circ}$ C, unless otherwise specified.1.71 V \lt V_{DD} \lt 3.6 V.

[1] Based on the power API library from the SDK software package available on nxp.com.

[2] Typical ratings are not guaranteed. Typical values listed are at room temperature (25 °C), 3.3V.

- [3] Clock source FRO. PLL disabled.
- [4] Characterized through bench measurements using typical samples.
- [5] Compiler settings: Keil uVision v.5.21, optimization level 0, optimized for time off.
- [6] Acceleration enable bit in the FLASHCFG register is set to 0. SRAM0 powered. SRAM1, SRAM2, SRAM3, USB SRAM and SRAMX powered down.
- [7] Flash is powered down; SRAM0 and SRAMX are powered; SRAM1, SRAM2, SRAM3, and USB SRAM are powered down. All peripheral clocks disabled.
- [8] Clock source FRO. PLL enabled.
- [9] At 220 MHz the system clock/access time can be lower when compared to 180 MHz because the power library optimizes the on-chip voltage regulator.

CoreMark µA/MHz from flash: SRAM1, SRAM2, SRAM3, and USB SRAM powered down. SRAM0 and SRAMX powered.

CoreMark µA/MHz from SRAMX: SRAM0 is powered; flash is powered down.

Fig 15. CoreMark power consumption: typical A/MHz vs. frequency (MHz) from flash and SRAMX

Table 16. Static characteristics: Power consumption in deep-sleep and deep power-down modes T_{amb} = -40 °C to +105 °C, unless otherwise specified, 1.71 $V \leq V_{DD} \leq 2.7 V$.

Symbol	Parameter	Conditions		Min	Typ ^{[1][2]}	Max ^[3]	Unit	
l _{DD}	supply current	Deep-sleep mode; Flash is powered down						
		SRAMX (32 KB) powered			22	69	μA	
		T_{amb} = 25 °C						
		SRAMX (32 KB) powered T_{amb} = 105 °C				1150	μA	
		Deep power-down mode						
		RTC oscillator input grounded (RTC oscillator disabled)			326	1000	nA	
		$T_{amb} = 25 \degree C$						
		RTC oscillator input grounded (RTC oscillator disabled)				27	μA	
		$T_{\text{amb}} = 105 \degree C$						
		RTC oscillator running with external crystal $VDD = VDDA = VREFP = VBAT = 1.8 V$			340		nA	

[1] Typical ratings are not guaranteed. Typical values listed are at room temperature (25 °C), VDD = 1.8 V.

[2] Characterized through bench measurements using typical samples.

[3] Tested in production. VDD = 1.71 V. At hot temperature and below 2.0 V, the supply current could increase slightly because of reduction of available RBB (reverse body bias) voltage.

Table 17. Static characteristics: Power consumption in deep-sleep and deep power-down modes T_{amb} = -40 °C to +105 °C, unless otherwise specified, 2.7 $V \leq V_{DD} \leq 3.6$ V.

[1] Typical ratings are not guaranteed. Typical values listed are at room temperature (25 °C), VDD = 3.3 V.

[2] Characterized through bench measurements using typical samples.

[3] Tested in production, VDD = 3.6 V.

Table 18. Static characteristics: Power consumption in deep power-down mode

T_{amb} = -40 °C to +105 °C, unless otherwise specified, 2.7 $V \le V_{DD} \le 3.6$ V.

[1] Typical ratings are not guaranteed. Typical values listed are at room temperature (25 °C).

[2] Characterized through bench measurements using typical samples.

[3] If VBAT> VDD, the external reset pin must be floating to prevent high VBAT leakage.

[Table 19](#page-93-0) shows the typical peripheral power consumption measured on a typical sample at Tamb = 25 °C and VDD = 3.3 V. The supply current per peripheral is measured as the difference in supply current between the peripheral block enabled and the peripheral block disabled using ASYNCAPBCLKCTRL, AHBCLKCTRL0/1/2, and PDRUNCFG0/1

registers. All other blocks are disabled and no code accessing the peripheral is executed. The supply currents are shown for system clock frequencies of 12 MHz, 48 MHz, 96 MHz and 180MHz.

Table 19. Typical peripheral power consumption[\[1\]](#page-93-1)[\[2\]](#page-93-2)

 $V_{DD} = 3.3 \text{ V}; T_{amb} = 25 \text{ }^{\circ}\text{C}$

[1] The supply current per peripheral is measured as the difference in supply current between the peripheral block enabled and the peripheral block disabled using PDRUNCFG0/1 registers. All other blocks are disabled and no code accessing the peripheral is executed.

[2] Typical ratings are not guaranteed. Characterized through bench measurements using typical samples.

Table 20. Typical AHB/APB peripheral power consumption [\[3\]](#page-95-1)[\[4\]](#page-95-2)[\[5\]](#page-95-3)

 $T_{amb} = 25 °C$, $V_{DD} = 3.3 V$;

Table 20. Typical AHB/APB peripheral power consumption [3][4][5]

 $T_{amb} = 25 \degree C$, $V_{DD} = 3.3 V$;

Table 20. Typical AHB/APB peripheral power consumption [3][4][5]

 $T_{amb} = 25 \degree C$, $V_{DD} = 3.3 V$;

[1] Turn off the peripheral when the configuration is done.

- [2] For optimal system power consumption, use fixed low frequency Async APB bus when the CPU is at a higher frequency.
- [3] The supply current per peripheral is measured as the difference in supply current between the peripheral block enabled and the peripheral block disabled using ASYNCAPBCLKCTRL, AHBCLKCTRL0/1, and PDRUNCFG0/1 registers. All other blocks are disabled and no code accessing the peripheral is executed.
- [4] The supply currents are shown for system clock frequencies of 12 MHz, 48 MHz, 96 MHz, 180 MHz, and 220 MHz.
- [5] Typical ratings are not guaranteed. Characterized through bench measurements using typical samples.

10.5 Pin characteristics

Table 21. Static characteristics: pin characteristics

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. 1.71 V \leq V_{DD} \leq 3.6 V unless otherwise specified. Values tested in *production unless otherwise specified.*

Table 21. Static characteristics: pin characteristics *…continued*

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. 1.71 V \leq V_{DD} \leq 3.6 V unless otherwise specified. Values tested in *production unless otherwise specified.*

Table 21. Static characteristics: pin characteristics *…continued*

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. 1.71 V \leq V_{DD} \leq 3.6 V unless otherwise specified. Values tested in *production unless otherwise specified.*

[1] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltage.

[2] Based on characterization. Not tested in production.

[3] With respect to ground.

[4] Allowed as long as the current limit does not exceed the maximum current allowed by the device.

[5] To V_{SS} .

[6] The values specified are simulated and absolute values, including package/bondwire capacitance.

[7] The weak pull-up resistor is connected to the V_{DD} rail and pulls up the I/O pin to the V_{DD} level.

- [8] The value specified is a simulated value, excluding package/bondwire capacitance.
- [9] Without 33 $\Omega \pm 2$ % series external resistor.
- [10] The parameter values specified are simulated and absolute values.

[11] With 33 $\Omega \pm 2$ % series external resistor.

- [12] With 15 K $\Omega \pm 5$ % resistor to V_{SS}.
- [13] With 1.5 K Ω ± 5% resistor to 3.6 V external pull-up.
- [14] Guaranteed by design, not tested in production.

10.5.1 Electrical pin characteristics

11. Dynamic characteristics

11.1 Flash memory

Table 22. Flash characteristics

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. V_{DD} = 1.71 V to 3.6 V

[1] Number of erase/program cycles.

[2] Programming times are given for writing 256 bytes from RAM to the flash.

11.2 EEPROM

Table 23. EEPROM characteristics

 $T_{amb} = -40$ ^{\degree}C to +85 \degree C; $V_{DD} = 1.71$ V to 3.6 V.

[1] See the LPC546xx. user manual, UM10912 on how to program the wait states for the different read (RPHASEx) and erase/program phases (PHASEx).

Remark: EEPROM is not accessible in deep-sleep and deep power-down modes

11.3 I/O pins

Table 24. Dynamic characteristic: I/O pins[\[1\]](#page-102-0)

 T_{amb} = -40 °C to +105 °C; 1.71 $V \leq V_{DD} \leq 3.6$ V

[1] Simulated data, not tested in production.

[2] Simulated using 10 cm of 50 Ω PCB trace with 5 pF receiver input. Rise and fall times measured between 80 % and 20 % of the full output signal level.

- [3] The slew rate is configured in the IOCON block the SLEW bit. See the LPC546xx user manual.
- [4] C_L = 20 pF. Rise and fall times measured between 90 % and 10 % of the full input signal level.

11.4 Wake-up process

Table 25. Dynamic characteristic: Typical wake-up times from low power modes $V_{DD} = 3.3 V$; $T_{amb} = 25 °C$; using FRO as the system clock.

[1] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.

[2] The wake-up time measured is the time between when a GPIO input pin is triggered to wake the device up from the low power modes and from when a GPIO output pin is set in the interrupt service routine (ISR) wake-up handler.

- [3] FRO enabled, all peripherals off. PLL disabled.
- [4] RTC disabled. Wake up from deep power-down causes the part to go through entire reset process. The wake-up time measured is the time between when the RESET pin is triggered to wake the device up and when a GPIO output pin is set in the reset handler.

[5] FRO disabled.

11.5 External memory interface

Table 26. Dynamic characteristics: Static external memory interface

 C_L = 10 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB; Values based on simulation.*

Table 26. Dynamic characteristics: Static external memory interface *…continued*

 C_L = 10 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB; Values based on simulation.*

[1] Parameters are shown as RD_n or WD_n in [Figure 24](#page-107-0) as indicated in the Conditions column.

[2] Tcy(clk) = 1/EMC_CLK (see *UM10912* LPC546xx *manual*).

[3] Latest of address valid, $\overline{EMC_CSS}$ LOW, $\overline{EMC_OCE}$ LOW, $\overline{EMC_BLSx}$ LOW (PB = 1).

- [4] After End Of Read (EOR): Earliest of EMC_CSx HIGH, EMC_OE HIGH, EMC_BLSx HIGH (PB = 1), address invalid.
- [5] End Of Write (EOW): Earliest of address invalid, **EMC_CSx HIGH, EMC_BLSx HIGH (PB = 1)**.
- [6] The byte lane state bit, PB, enables different types of memory to be connected (see *the STATICCONFIG[0:3] register in the UM10912* LPC546xx *manual*).

Table 27. Dynamic characteristics: Static external memory interface

 C_L = 20 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB; Values based on simulation.*

Table 27. Dynamic characteristics: Static external memory interface *…continued*

 C_L = 20 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB; Values based on simulation.*

[1] Parameters are shown as RD_n or WD_n in **[Figure 24](#page-107-0)** as indicated in the Conditions column.

- [2] T_{cyclk} = 1/EMC_CLK (see *UM10912* LPC546xx manual).
- [3] Latest of address valid, $\overline{EMC_CCSx}$ LOW, $\overline{EMC_OE}$ LOW, $\overline{EMC_BLSx}$ LOW (PB = 1).
- [4] After End Of Read (EOR): Earliest of EMC_CSx HIGH, EMC_OE HIGH, EMC_BLSx HIGH (PB = 1), address invalid.
- [5] End Of Write (EOW): Earliest of address invalid, $\overline{EMC_CCSx}$ HIGH, $\overline{EMC_BLSx}$ HIGH (PB = 1).
- [6] The byte lane state bit, PB, enables different types of memory to be connected (see *the STATICCONFIG[0:3] register in the UM10912* LPC546xx *manual*).

Table 28. Dynamic characteristics: Dynamic external memory interface, read strategy bits (RD bits) = 01 [\[2\]](#page-109-1) C_L = 10 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB. Values based on simulation. tcmddly is programmable delay value for EMC* command outputs in command delayed mode; t_{fbdly} is programmable delay value for the feedback clock that controls input *data sampling.*

[1] Refers to SDRAM clock signal EMC_CLKOUTn where n = 0 and 1.

[2] See [Table 30](#page-112-0) for internal programmable delay.

Table 29. Dynamic characteristics: Dynamic external memory interface, read strategy bits (RD bits) = 01 [\[2\]](#page-110-1) C_L = 20 pF balanced loading on all pins, T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Max EMC clock = 100 MHz. Input *slew = 1 ns; SLEW set to fast-mode. Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Excluding delays introduced by external device and PCB. Values based on simulation. tcmddly is programmable delay value for EMC* command outputs in command delayed mode; t_{fbdly} is programmable delay value for the feedback clock that controls input *data sampling.*

[1] Refers to SDRAM clock signal EMC_CLKOUTn where n = 0 and 1.

[2] See [Table 30](#page-112-0) for internal programmable delay.

Table 30. Dynamic characteristics: Dynamic external memory interface programmable clock delays (CMDDLY, FBCLKDLY)

 T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. Values guaranteed by design. t_{cmddy} is programmable delay value for EMC command outputs in command delayed mode; t_{fbdly} is programmable delay value for the feedback clock that controls input *data sampling.*

[1] The programmable delay blocks are controlled by the EMCDLYCTL register in the EMC register block. All delay times are incremental delays for each element starting from delay block 0. See the *LPC546xx. user manual* for details.

11.6 System PLL (PLL0)

Table 31. PLL lock times and current

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. V_{DD} = 1.71 V to 3.6 V

[1] Data based on characterization results, not tested in production.

[2] PLL current measured using lowest CCO frequency to obtain the desired output frequency.

Table 32. Dynamic characteristics of the PLL0[\[1\]](#page-113-2)

[1] Data based on characterization results, not tested in production.

[2] Excluding under- and overshoot which may occur when the PLL is not in lock.

[3] A phase difference between the inputs of the PFD (clkref and clkfb) smaller than the PFD lock criterion means lock output is HIGH.

[4] Actual jitter dependent on amplitude and spectrum of substrate noise.

[5] Input clock coming from a crystal oscillator with less than 250 ps peak-to-peak period jitter.

11.7 USB PLL (PLL1)

Table 33. PLL1 lock times and current

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. V_{DD} = 1.71 V to 3.6 V

Symbol	Parameter	Conditions		Min	Tvp	Max	Unit	
PLL1 configuration: input frequency 12 MHz; output frequency 48 MHz								
I _{lock} (PLL1)	PLL1 lock time				7.4		uS	
DD(PLL1)	PLL1 current	When locked	[1][2]		260		μA	

[1] Data based on characterization results, not tested in production.

[2] PLL current measured using lowest CCO frequency to obtain the desired output frequency.

Table 34. Dynamic characteristics of the PLL1[\[1\]](#page-114-5)

[1] Data based on simulation, not tested in production.

[2] Excluding under- and overshoot which may occur when the PLL is not in lock.

- [3] Actual jitter dependent on amplitude and spectrum of substrate noise.
- [4] Input clock coming from a crystal oscillator with less than 250 ps peak-to-peak period jitter.

11.8 Audio PLL (PLL2)

Table 35. PLL2 lock times and current

 T_{amb} = -40 °C to +105 °C, unless otherwise specified. V_{DD} = 1.71 V to 3.6 V

[1] Data based on characterization results, not tested in production.

[2] PLL current measured using lowest CCO frequency to obtain the desired output frequency.

Table 36. Dynamic characteristics of the PLL2[\[1\]](#page-113-2)

[1] Data based on characterization results, not tested in production.

- [2] Excluding under- and overshoot which may occur when the PLL is not in lock.
- [3] A phase difference between the inputs of the PFD (clkref and clkfb) smaller than the PFD lock criterion means lock output is HIGH.
- [4] Actual jitter dependent on amplitude and spectrum of substrate noise.
- [5] Input clock coming from a crystal oscillator with less than 250 ps peak-to-peak period jitter.

11.9 FRO

The FRO is trimmed to ± 1 % accuracy over the entire voltage and temperature range.

Table 37. Dynamic characteristic: FRO

 $\mathsf{f}_{\mathsf{osc}(\mathsf{RC})}$ FRO clock frequency $\vert\text{-}$ 47.52 48 48.48 MHz $f_{\text{osc(RC)}}$ FRO clock frequency \vert - 95.04 96 96.96 MHz

[1] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.

11.10 Crystal oscillator

Table 38. Dynamic characteristic: oscillator

Table 38. Dynamic characteristic: oscillator *…continued*

- [1] Parameters are valid over operating temperature range unless otherwise specified.
- [2] Typical ratings are not guaranteed. The values listed are at room temperature (25 \degree C), nominal supply voltages.
- [3] Indicates RMS period jitter.
- [4] Select Low Frequency range = 0 in the SYSOSCCTRL register.
- [5] Select High Frequency = 1 in the SYSOSCCTRL register.

11.11 RTC oscillator

See [Section 13.5](#page-147-0) for connecting the RTC oscillator to an external clock source.

Table 39. Dynamic characteristic: RTC oscillator

 $T_{amb} = -40$ [°]C to +105 [°]C; 1.71 \leq V_{DD} \leq 3.6^{[\[1\]](#page-116-5)}

- [1] Parameters are valid over operating temperature range unless otherwise specified.
- [2] Typical ratings are not guaranteed. The values listed are at room temperature (25 \degree C), nominal supply voltages.

11.12 Watchdog oscillator

Table 40. Dynamic characteristics: Watchdog oscillator

 $T_{amb} = -40$ *°C to +105 °C; 1.71* \leq *V_{DD}* \leq *3.6*^{[\[1\]](#page-116-5)}

[1] Typical ratings are not guaranteed. The values listed are at nominal supply voltages.

[2] The typical frequency spread over processing and temperature (T_{amb} = -40 °C to +105 °C) is \pm 40 %.

[3] Actual jitter dependent on amplitude and spectrum of substrate noise.

[4] Guaranteed by design. Not tested in production samples.

11.13 I2C-bus

Table 41. Dynamic characteristic: I2C-bus pins[\[1\]](#page-118-0)

 $T_{amb} = -40$ ^oC to +105 ^oC; 1.71 $V \leq V_{DD} \leq 3.6$ V.^{[\[2\]](#page-118-1)}

[1] Guaranteed by design. Not tested in production.

- [2] Parameters are valid over operating temperature range unless otherwise specified. See the I2C-bus specification *UM10204* for details.
- [3] tHD;DAT is the data hold time that is measured from the falling edge of SCL; applies to data in transmission and the acknowledge.
- [4] A device must internally provide a hold time of at least 300 ns for the SDA signal (with respect to the V_{IH}(min) of the SCL signal) to bridge the undefined region of the falling edge of SCL.
- $[5]$ C_b = total capacitance of one bus line in pF. If mixed with Hs-mode devices, faster fall times are allowed.
- [6] The maximum t_f for the SDA and SCL bus lines is specified at 300 ns. The maximum fall time for the SDA output stage t_f is specified at 250 ns. This allows series protection resistors to be connected in between the SDA and the SCL pins and the SDA/SCL bus lines without exceeding the maximum specified t_f .
- [7] In Fast-mode Plus, fall time is specified the same for both output stage and bus timing. If series resistors are used, designers should allow for this when considering bus timing.
- [8] The maximum t_{HD;DAT} could be 3.45 us and 0.9 us for Standard-mode and Fast-mode but must be less than the maximum of t_{VD;DAT} or $t_{VD:ACK}$ by a transition time. This maximum must only be met if the device does not stretch the LOW period (t_{LOW}) of the SCL signal. If the clock stretches the SCL, the data must be valid by the set-up time before it releases the clock.
- [9] tSU;DAT is the data set-up time that is measured with respect to the rising edge of SCL; applies to data in transmission and the acknowledge.
- [10] A Fast-mode I²C-bus device can be used in a Standard-mode I²C-bus system but the requirement $t_{\text{SU,DAT}} = 250$ ns must then be met. This will automatically be the case if the device does not stretch the LOW period of the SCL signal. If such a device does stretch the LOW period of the SCL signal, it must output the next data bit to the SDA line $t_{r(max)} + t_{SU;DAT} = 1000 + 250 = 1250$ ns (according to the Standard-mode I²C-bus specification) before the SCL line is released. Also the acknowledge timing must meet this set-up time.

11.14 I2S-bus interface

Table 42. Dynamic characteristics: I2S-bus interface pins [\[1\]](#page-121-4)[\[4\]](#page-121-0)

 T_{amb} = -40 °C to 105 °C; V_{DD} = 1.71 V to 3.6 V; C_L = 30 pF balanced loading on all pins; Input slew = 1.0 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 50 % level of the rising or falling edge.*

Table 42. Dynamic characteristics: I2S-bus interface pins [1][4]

 T_{amb} = -40 °C to 105 °C; V_{DD} = 1.71 V to 3.6 V; C_L = 30 pF balanced loading on all pins; Input slew = 1.0 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 50 % level of the rising or falling edge.*

- [1] Based on characterization; not tested in production.
- [2] Clock Divider register (DIV) = 0x0.
- [3] Typical ratings are not guaranteed.
- [4] The Flexcomm Interface function clock frequency should not be above 48 MHz. See the data rates section in the I2S chapter (UM10912) to calculate clock and sample rates.
- [5] Based on simulation. Not tested in production.

11.15 SPI interfaces

The actual SPI bit rate depends on the delays introduced by the external trace, the external device, system clock (CCLK), and capacitive loading. Excluding delays introduced by external device and PCB, the maximum supported bit rate for SPI master mode is 48 Mbit/s, and the maximum supported bit rate for SPI slave mode is 14 Mbit/s.

Table 43. SPI dynamic characteristics[\[1\]](#page-123-0)

 T_{amb} = -40 °C to 105 °C; 1.71 $V \le V_{DD} \le 3.6$ V; C_l = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW setting = *standard mode for all pins;. Parameters sampled at the 50 % level of the rising or falling edge.*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit				
SPI master 1.71 $V \leq V_{DD} \leq 2.7 V$										
t_{DS}	data set-up time	$CCLK \leq 100 MHz$	2.2			ns				
		100 MHz < CCLK ≤ 180 MHz	1.9			ns				
t_{DH}	data hold time	$CCLK \leq 100 MHz$	6.3			ns				
		100 MHz < CCLK ≤ 180 MHz	6.7			ns				
$t_{v(Q)}$	data output valid time	$CCLK \leq 100 MHz$	2.6		5.0	ns				
		100 MHz < CCLK ≤ 180 MHz	0.3		4.7	ns				
	SPI slave 1.71 $V \leq V_{DD} \leq 2.7 V$									
t_{DS}	data set-up time	$CCLK \leq 100 MHz$	1.1			ns				
		100 MHz < CCLK ≤ 180 MHz	0.9			ns				
t_{DH}	data hold time	$CCLK \leq 100 MHz$	2.1			ns				
		100 MHz < CCLK \leq 180 MHz	2.2			ns				
$t_{v(Q)}$	data output valid time	$CCLK \leq 100 MHz$	18.8		37.0	ns				
		100 MHz < CCLK ≤ 180 MHz	18.0		36.0	ns				
SPI master 2.7 $V \leq V_{DD} \leq 3.6 V$										
t_{DS}	data set-up time	$CCLK \leq 100 MHz$	2.4			ns				
		100 MHz < CCLK ≤ 180 MHz	2.2			ns				
t_{DH}	data hold time	$CCLK \leq 100 MHz$	4.2			ns				
		100 MHz < CCLK ≤ 180 MHz	4.5			ns				
$t_{v(Q)}$	data output valid time	$CCLK \leq 100 MHz$	1.8		4.6	ns				
		100 MHz < CCLK ≤ 180 MHz	1.7		4.0	ns				
	SPI slave 2.7 $V \leq V_{DD} \leq 3.6 V$									
t_{DS}	data set-up time	$CCLK \leq 100 MHz$	1.2			ns				
		100 MHz < CCLK ≤ 180 MHz	1.0			ns				
∣t _{DH}	data hold time	$CCLK \leq 100 MHz$	0			ns				
		100 MHz < CCLK ≤ 180 MHz	$\mathbf 0$			ns				
$t_{v(Q)}$	data output valid time	$CCLK \leq 100 MHz$	14		23.9	ns				
		100 MHz < CCLK ≤ 180 MHz	13.3		22.2	ns				

[1] Based on characterization; not tested in production.

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11.16 SPIFI

The actual SPIFI bit rate depends on the delays introduced by the external trace, the external device, system clock (CCLK), and capacitive loading. Excluding delays introduced by external device and PCB, the maximum supported bit rate for SPIFI mode is 100 Mbit/s.

Table 44. Dynamic characteristics: SPIFI[\[1\]](#page-126-0)

 T_{amb} = -40 °C to 105 °C; V_{DD} = 1.71 V to 3.6 V; C_l = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW set to *standard mode for all pins; Parameters sampled at the 50 % level of the rising or falling edge. Maximum SPIFI clock = 100 MHZ*

[1] Based on simulation; not tested in production.

11.17 DMIC subsystem

Table 45. Dynamic characteristics[\[1\]](#page-127-0)

 T_{amb} = -40 °C to 105 °C; V_{DD} = 2.7 V to 3.6 V; C_L = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW set to *standard mode for all pins; Bypass bit = 0; Parameters sampled at the 90 % and 10 % level of the rising or falling edge.*

[1] Based on simulated values.

11.18 Smart card interface

Table 46. Dynamic characteristics[\[1\]](#page-128-0)

 T_{amb} = -40 \degree C to 105 \degree C; V_{DD} = 1.71 V to 3.6 V; C_L = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 90 % and 10 % level of the rising or falling edge.*

[1] Based on simulated values. $V_{DD} = 2.7 V - 3.6 V$.

11.19 USART interface

The actual USART bit rate depends on the delays introduced by the external trace, the external device, system clock (CCLK), and capacitive loading. Excluding delays introduced by external device and PCB, the maximum supported bit rate for USART master synchronous mode is 24 Mbit/s, and the maximum supported bit rate for USART slave synchronous mode is 12.5 Mbit/s.

Table 47. USART dynamic characteristics[\[1\]](#page-129-0)

 T_{amb} = -40 °C to 105 °C; V_{DD} = 1.71 V to 3.6 V; C_L = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 50 % level of the rising or falling edge.*

[1] Based on characterization; not tested in production.

11.20 SCTimer/PWM output timing

Table 48. SCTimer/PWM output dynamic characteristics

 T_{amb} = -40 °C to 105 °C; 1.71 V \leq V_{DD} \leq 3.6 V C_L = 30 pF. Simulated skew (over process, voltage, and temperature) of any *two SCT fixed-pin output signals; sampled at the 90 % and 10 % level of the rising or falling edge; values guaranteed by design.*

11.21 USB interface characteristics

Table 49. Dynamic characteristics: USB0 pins (full-speed)

 C_l = 50 pF; R_{p0} = 1.5 k Ω on D+ to V_{DD} , unless otherwise specified; 3.0 V \leq V_{DD} \leq 3.6 V.

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
t _r	rise time	10 % to 90 %		4.0		20	ns
t_f	fall time	10 % to 90 %		4.0		20	ns
IFRFM	differential rise and fall time matching	t_r / t_f		90		111.11	$\%$
V_{CRS}	output signal crossover voltage			1.3		2.0	v
^t FEOPT	source SE0 interval of EOP	see Figure 36		160		175	ns
^t FDEOP	source jitter for differential transition to SE0 transition	see Figure 36		-2		$+5$	ns
$t_{\rm JR1}$	receiver jitter to next transition			-18.5		$+18.5$	ns
t_{JR2}	receiver jitter for paired transitions	10 % to 90 %		-9		$+9$	ns
t _{EOPR1}	EOP width at receiver	must reject as EOP; see Figure 36	$\boxed{1}$	40			ns
t _{EOPR2}	EOP width at receiver	must accept as EOP; see Figure 36	$[1]$	82			ns

[1] Characterized but not implemented as production test. Guaranteed by design.

11.23 Ethernet AVB

Remark: The timing characteristics of the ENET_MDC and ENET_MDIO signals comply with the *IEEE standard 802.3*.

Table 50. Dynamic characteristics: Ethernet

 T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. C_L = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Based on simulation.*

Table 50. Dynamic characteristics: Ethernet

 T_{amb} = -40 °C to 105 °C, V_{DD} = 2.7 V to 3.6 V. C_L = 30 pF balanced loading on all pins; Input slew = 1 ns, SLEW setting = *standard mode for all pins; Parameters sampled at the 90 % and 10 % level of the rising or falling edge. Based on simulation.*

[1] Output drivers can drive a load \geq 25 pF accommodating over 12 inch of PCB trace and the input capacitance of the receiving device.

[2] Timing values are given from the point at which the clock signal waveform crosses 1.4 V to the valid input or output level.

11.24 SD/MMC and SDIO

Table 51. Dynamic characteristics: SD/MMC and SDIO

 T_{amb} = -40 °C to +105 °C, V_{DD} = 2.7 V to 3.6 V; C_L = 20 pF. SAMPLE_DELAY = 0, DRV_DELAY = 0 in the SDDELAY *register, SDIOCLKCTRL = 0x84, sampled at 90 % and 10 % of the signal level, SLEW = 1 ns for SD_CLK pin, SLEW = 1 ns for SD_DATn and SD_CMD pins. Simulated values in high-speed mode.*

11.25 LCD

Table 52. Dynamic characteristics: LCD

 T_{amb} = -40 °C to 105 °C; V_{DD} = 2.7 V to 3.6 V; C_L = 30 pF. Simulated values.

12. Analog characteristics

12.1 BOD

Table 53. BOD static characteristics

Tamb = 25 C; based on characterization; not tested in production.

12.2 12-bit ADC characteristics

Table 54. 12-bit ADC static characteristics

 $T_{\text{amb}} = -40$ °C to +105 °C; 1.71 $V \le V_{DD} \le 3.6$ V; $V_{SSA} = VREFN = GND$. ADC calibrated at $T_{\text{amb}} = 25$ °C.

[1] Based on characterization; not tested in production.

- [2] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.
- [3] The input resistance of ADC channels 6 to 11 is higher than ADC channels 0 to 5.
- $[4]$ C_{ia} represents the external capacitance on the analog input channel for sampling speeds of 5.0 Msamples/s. No parasitic capacitances included.
- [5] The differential linearity error (E_D) is the difference between the actual step width and the ideal step width. See [Figure 40.](#page-137-3)
- [6] The integral non-linearity ($E_{L(adj)}$) is the peak difference between the center of the steps of the actual and the ideal transfer curve after appropriate adjustment of gain and offset errors. See [Figure 40](#page-137-3).
- [7] The offset error (E_0) is the absolute difference between the straight line which fits the actual curve and the straight line which fits the ideal curve. See [Figure 40](#page-137-3).

- [8] The full-scale error voltage or gain error (E_G) is the difference between the straight-line fitting the actual transfer curve after removing offset error, and the straight line which fits the ideal transfer curve. See [Figure 40](#page-137-3).
- [9] T_{amb} = 25 °C; maximum sampling frequency f_s = 5.0 Msamples/s and analog input capacitance C_{ia} = 5 pF.
- [10] Input impedance Z_i is inversely proportional to the sampling frequency and the total input capacity including C_{ia} and C_{io} : $Z_i \propto 1$ / ($f_s \times C_i$). See [Table 21](#page-95-0) for C_{io} . See [Figure 41.](#page-140-0)

Table 55. ADC sampling times[\[1\]](#page-139-0)

 -40 $°C \leq T_{amb} \leq 85$ $°C$; 1.71 $V \leq V_{DDA} \leq 3.6$ V; 1.71 $V \leq V_{DD} \leq 3.6$ V

Symbol	Parameter	Conditions		Min	Typ	Max	Unit	
ADC inputs ADC_5 to ADC_0 (fast channels); ADC resolution = 12 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	$[3]$	20			ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		23			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		26			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		31			ns	
		0.5 kΩ <= Z _o < 1 kΩ		47			ns	
		1 k Ω <= Z_0 < 5 k Ω		75			ns	
ADC inputs ADC_5 to ADC_0 (fast channels); ADC resolution = 10 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 k Ω	$[3]$	15			ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		18			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		20			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		24			ns	
		$0.5 \text{ k}\Omega \le Z_0 \le 1 \text{ k}\Omega$		38			ns	
		1 kΩ <= Z_0 < 5 kΩ		62			ns	
		ADC inputs ADC_5 to ADC_0 (fast channels); ADC resolution = 8 bit						
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	$[3]$	12			ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		13			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		15			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		19			ns	
		0.5 kΩ <= Z _o < 1 kΩ		30			ns	
		1 k Ω <= Z_0 < 5 k Ω		48			ns	
ADC inputs ADC_5 to ADC_0 (fast channels); ADC resolution = 6 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	$[3]$	9			ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		10			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		11			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		13	\overline{a}		ns	
		0.5 kΩ <= Z _o < 1 kΩ		22			ns	
		1 k Ω <= Z_0 < 5 k Ω		36			ns	
ADC inputs ADC_11 to ADC_6 (slow channels); ADC resolution = 12 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	$[3]$	43			ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		46			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		50			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		56			ns	
		0.5 kΩ <= Z _o < 1 kΩ		74			ns	
		1 kΩ <= Z_0 < 5 kΩ		105	\overline{a}		ns	

Table 55. ADC sampling times[1] *…continued*

-40 C Tamb <= 85 C; 1.71 V VDDA 3.6 V; 1.71 V VDD 3.6 V

Symbol	Parameter	Conditions		Min	Typ	Max	Unit	
ADC inputs ADC_11 to ADC_6 (slow channels); ADC resolution = 10 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	[3]	35	$\overline{}$	$\overline{}$	ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		38			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		40			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		46			ns	
		$0.5 \text{ k}\Omega \le Z_0 \le 1 \text{ k}\Omega$		61			ns	
		1 k Ω <= Z_0 < 5 k Ω		86			ns	
		ADC inputs ADC_11 to ADC_6 (slow channels); ADC resolution = 8 bit						
t_{s}	sampling time	Z_0 < 0.05 kΩ	[3]	27	$\overline{}$	$\overline{}$	ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		29			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		32			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		36	$\overline{}$		ns	
		$0.5 \text{ k}\Omega \le Z_0 \le 1 \text{ k}\Omega$		48			ns	
		1 k Ω <= Z_0 < 5 k Ω		69			ns	
ADC inputs ADC_11 to ADC_6 (slow channels); ADC resolution = 6 bit								
$ t_{s} $	sampling time	Z_0 < 0.05 kΩ	[3]	20	$\overline{}$	$\overline{}$	ns	
		$0.05 \text{ k}\Omega \le Z_0 \le 0.1 \text{ k}\Omega$		22			ns	
		$0.1 \text{ k}\Omega \le Z_0 \le 0.2 \text{ k}\Omega$		23			ns	
		$0.2 \text{ k}\Omega \le Z_0 \le 0.5 \text{ k}\Omega$		26	\overline{a}		ns	
		$0.5 \text{ k}\Omega \le Z_0 \le 1 \text{ k}\Omega$		36	Ξ.		ns	
		1 k Ω <= Z_0 < 5 k Ω		51			ns	

- [1] Characterized through simulation. Not tested in production.
- [2] The ADC default sampling time is 2.5 ADC clock cycles. To match a given analog source output impedance, the sampling time can be extended by adding up to seven ADC clock cycles for a maximum sampling time of 9.5 ADC clock cycles. See the TSAMP bits in the ADC CTRL register.
- [3] Z_0 = analog source output impedance.
- [4] For VDD \leq 2.5 V, add one additional clock cycle to the values in [Table 55.](#page-138-0)

12.2.1 ADC input impedance

[Figure 41](#page-140-0) shows the ADC input impedance. In this figure:

- **•** ADCx represents slow ADC input channels 6 to 11.
- **•** ADCy represents fast ADC input channels 0 to 5.
- R_1 and R_{sw} are the switch-on resistance on the ADC input channel.
- **•** If fast channels (ADC inputs 0 to 5) are selected, the ADC input signal goes through R_{sw} to the sampling capacitor (C_{ia}).
- **•** If slow channels (ADC inputs 6 to 11) are selected, the ADC input signal goes through R_1 + R_{sw} to the sampling capacitor (C_{ia}).
- Typical values, R_1 = 487 Ω , R_{sw} = 278 Ω
- See [Table 21](#page-95-0) for C_{io}.
- See [Table 54](#page-136-7) for C_{ia}.

12.3 Temperature sensor

Table 56. Temperature sensor static and dynamic characteristics $V_{DD} = V_{DDA} = 1.71$ V to 3.6 V

[1] Absolute temperature accuracy.

[2] Based on simulation.

Table 57. Temperature sensor Linear-Least-Square (LLS) fit parameters $V_{DD} = V_{DDA} = 1.71$ V to 3.6 V

[1] Measured over typical samples.

[2] Measured for samples over process corners.

13. Application information

13.1 Start-up behavior

[Figure 43](#page-142-0) shows the start-up timing after reset. The FRO 12 MHz oscillator provides the default clock at Reset and provides a clean system clock shortly after the supply pins reach operating voltage.

Table 58. Typical start-up timing parameters

13.2 Standard I/O pin configuration

[Figure 44](#page-143-0) shows the possible pin modes for standard I/O pins:

- **•** Digital output driver: enabled/disabled.
- **•** Digital input: Pull-up enabled/disabled.
- **•** Digital input: Pull-down enabled/disabled.
- **•** Digital input: Repeater mode enabled/disabled.
- **•** Z mode; High impedance (no cross-bar currents for floating inputs).

The default configuration for standard I/O pins is Z mode. The weak MOS devices provide a drive capability equivalent to pull-up and pull-down resistors.

13.3 Connecting power, clocks, and debug functions

[Figure 45](#page-145-0) shows the basic board connections used to power the LPC546xx. devices, connect the external crystal and the 32 kHz oscillator for the RTC, and provide debug capabilities via the serial wire port.

- (7) Position the decoupling capacitor of 0.1 μ F as close as possible to the V_{BAT} pin. Tie V_{BAT} to V_{DD} if not used.
- **Fig 45. Power, clock, and debug connections**

13.4 I/O power consumption

I/O pins are contributing to the overall dynamic and static power consumption of the part. If pins are configured as digital inputs, a static current can flow depending on the voltage level at the pin and the setting of the internal pull-up and pull-down resistors. This current can be calculated using the parameters R_{pu} and R_{pd} given in [Table 21](#page-95-0) for a given input voltage V_I. For pins set to output, the current drive strength is given by parameters I_{OH} and I_{O} in [Table 21](#page-95-0), but for calculating the total static current, you also need to consider any external loads connected to the pin.

I/O pins also contribute to the dynamic power consumption when the pins are switching because the V_{DD} supply provides the current to charge and discharge all internal and external capacitive loads connected to the pin in addition to powering the I/O circuitry.

The contribution from the I/O switching current I_{sw} can be calculated as follows for any given switching frequency f_{sw} if the external capacitive load (C_{ext}) is known (see [Table 21](#page-95-0) for the internal I/O capacitance):

 I_{sw} = V_{DD} x f_{sw} x $(C_{io} + C_{ext})$

13.5 RTC oscillator

In the RTC oscillator circuit, only the crystal (XTAL) and the capacitances C_{X1} and C_{X2} need to be connected externally on RTCXIN and RTCXOUT. See [Figure 46](#page-147-0).

For best results, it is very critical to select a matching crystal for the on-chip oscillator. Load capacitance (CL), series resistance (RS), and drive level (DL) are important parameters to consider while choosing the crystal. After selecting the proper crystal, the external load capacitor C_{X1} and C_{X2} values can also be generally determined by the following expression:

 C_{X1} = C_{X2} = $2C_L$ – (C_{Pad} + $C_{Parasitic}$)

Where:

C_L - Crystal load capacitance

 C_{Pad} - Pad capacitance of the RTCXIN and RTCXOUT pins (~3 pF).

 $C_{Parasitic}$ – Parasitic or stray capacitance of external circuit.

Although C_{Parasitic} can be ignored in general, the actual board layout and placement of external components influences the optimal values of external load capacitors. Therefore, it is recommended to fine tune the values of external load capacitors on actual hardware board to get the accurate clock frequency. For fine tuning, output the RTC Clock to the CLOCKOUT pin and optimize the values of external load capacitors for minimum frequency deviation.

13.5.1 RTC Printed Circuit Board (PCB) design guidelines

- **•** Connect the crystal and external load capacitors on the PCB as close as possible to the oscillator input and output pins of the chip.
- **•** The length of traces in the oscillation circuit should be as short as possible and must not cross other signal lines.
- **•** Ensure that the load capacitors CX1, CX2, and CX3, in case of third overtone crystal usage, have a common ground plane.
- **•** Loops must be made as small as possible to minimize the noise coupled in through the PCB and to keep the parasitics as small as possible.
- **•** Lay out the ground (GND) pattern under crystal unit.
- **•** Do not lay out other signal lines under crystal unit for multi-layered PCB.

13.6 XTAL oscillator

In the XTAL oscillator circuit, only the crystal (XTAL) and the capacitances C_{X1} and C_{X2} need to be connected externally on XTALIN and XTALOUT. See [Figure 47.](#page-149-1)

For best results, it is very critical to select a matching crystal for the on-chip oscillator. Load capacitance (CL), series resistance (RS), and drive level (DL) are important parameters to consider while choosing the crystal. After selecting the proper crystal, the external load capacitor C_{X1} and C_{X2} values can also be generally determined by the following expression:

 C_{X1} = C_{X2} = 2C_L – (C_{Pad} + C_{Parasitic})

Where:

 C_1 - Crystal load capacitance

 C_{Pad} - Pad capacitance of the XTALIN and XTALOUT pins (~3 pF).

 $C_{Parasitic}$ – Parasitic or stray capacitance of external circuit.

Although $C_{Parasitic}$ can be ignored in general, the actual board layout and placement of external components influences the optimal values of external load capacitors. Therefore, it is recommended to fine tune the values of external load capacitors on actual hardware board to get the accurate clock frequency. For fine tuning, measure the clock on the XTALOUT pin and optimize the values of external load capacitors for minimum frequency deviation.

13.6.1 XTAL Printed Circuit Board (PCB) design guidelines

- **•** Connect the crystal and external load capacitors on the PCB as close as possible to the oscillator input and output pins of the chip.
- **•** The length of traces in the oscillation circuit should be as short as possible and must not cross other signal lines.
- **•** Ensure that the load capacitors CX1, CX2, and CX3, in case of third overtone crystal usage, have a common ground plane.
- **•** Loops must be made as small as possible to minimize the noise coupled in through the PCB and to keep the parasitics as small as possible.
- **•** Lay out the ground (GND) pattern under crystal unit.
- **•** Do not lay out other signal lines under crystal unit for multi-layered PCB.

13.7 Suggested USB interface solutions

The USB device can be connected to the USB as self-powered device (see [Figure 48\)](#page-151-0) or bus-powered device (see [Figure 49](#page-151-1)).

On the LPC546xx, the USB_VBUS pin is 5 V tolerant only when V_{DD} is applied and at operating voltage level. Therefore, if the USB_VBUS function is connected to the USB connector and the device is self-powered, the USB_VBUS pin must be protected for situations when $V_{DD} = 0$ V.

If V_{DD} is always at operating level while VBUS = 5 V, the USB VBUS pin can be connected directly to the VBUS pin on the USB connector.

For systems where V_{DD} can be 0 V and VBUS is directly applied to the VBUS pin, precautions must be taken to reduce the voltage to below 3.6 V, which is the maximum allowable voltage on the USB_VBUS pin in this case.

One method is to use a voltage divider to connect the USB_VBUS pin to the VBUS on the USB connector. The voltage divider ratio should be such that the USB_VBUS pin is greater than 0.7 V_{DD} to indicate a logic HIGH while below the 3.6 V allowable maximum voltage.

For the following operating conditions

 $VBUS_{max} = 5.25 V$ V_{DD} = 3.6 V,

the voltage divider should provide a reduction of 3.6 V/5.25 V or ~0.686 V.

The internal pull-up (1.5 k Ω) can be enabled by setting the DCON bit in the DEVCMDSTAT register to prevent the USB from timing out when there is a significant delay between power-up and handling USB traffic. External circuitry is not required.

(1) Connect the regulator output to USB_VBUS. In this case, the USB_VBUS signal is HIGH whenever the part is powered.

(2) Connect the VBUS signal directly from the connector to the USB_VBUS pin. In this case, 5 V are applied to the USB_VBUS pin while the regulator is ramping up to supply V_{DD} . Since the USB_VBUS pin is only 5 V tolerant when V_{DD} is at operating level, this connection can degrade the performance of the part over its lifetime. Simulation shows that lifetime is reduced to 15 years at T_{amb} = 45 °C and 8 years at T_{amb} = 55 °C assuming that USB_VBUS = 5 V is applied continuously while V_{DD} = 0 V.

Fig 49. USB interface on a bus-powered device

14. Package outline

Fig 50. LQFP208 package

Fig 51. LQFP100 package

Fig 52. TFBGA180 package

TFBGA100: plastic thin fine-pitch ball grid array package; 100 balls; body 9 x 9 x 0.7 mm

Fig 53. TFBGA100 package

15. Soldering

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16. Abbreviations

17. References

- [1] LPC546xx. User manual UM10912.
- [2] LPC546xx. Errata sheet.
- [3] Technical note ADC design guidelines: http://www.nxp.com/documents/technical_note/TN00009.pdf

18. Revision history

Table 60. Revision history

Table 60. Revision history *…continued*

Table 60. Revision history *…continued*

Table 60. Revision history *…continued*

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21. Contents

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